

SKIROC2_CMS

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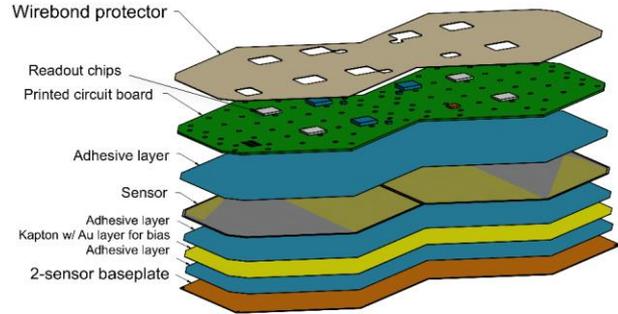
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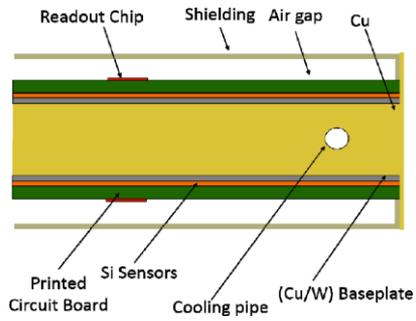


Modules

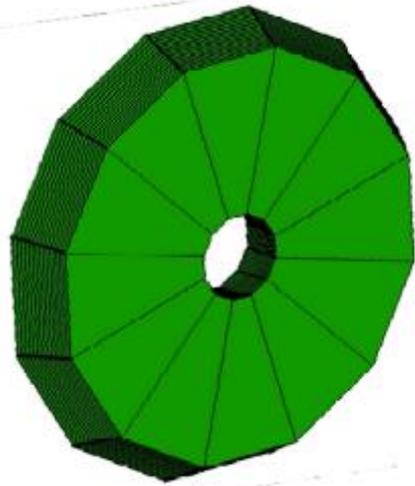
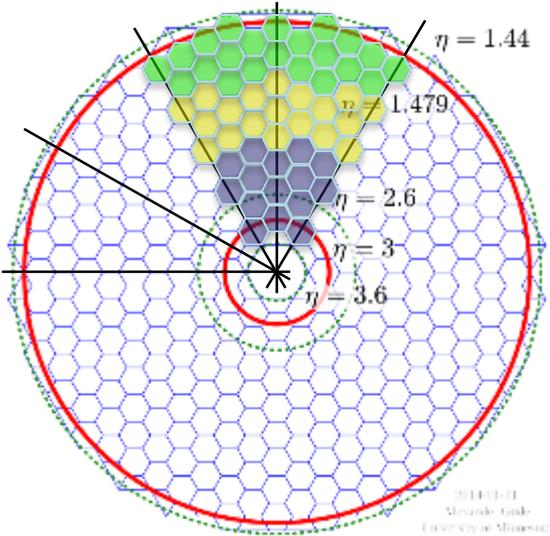
With 2x 6 - 8" Hexagonal Si sensors, PCB, FE chip, on W/Cu baseplate



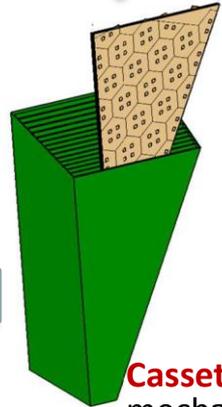
Modules mounted on Cu Cooling plate with embedded pipe
=> **Cassettes**



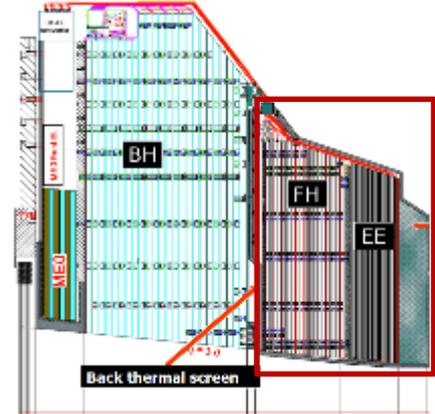
Final design still under development



12 **Cassettes** mounted together to form the **ECAL (EE)** and **Front HCal (FH)**



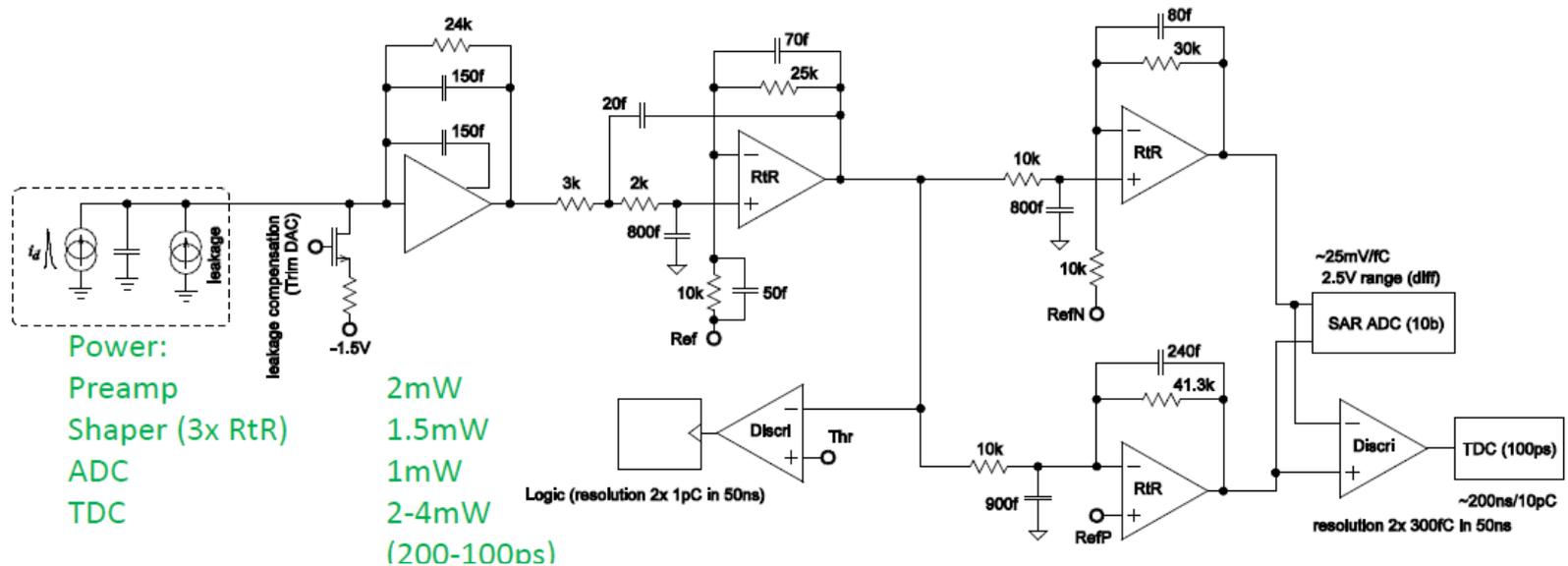
Cassette inserted in mechanical structure (containing absorber)



Replaced EndCap (maintained at -30°C)

3 sensor active thicknesses 100-200-300 μm
0.5-1 cm^2 pads for 100(-00/300) μm
Capacitance \sim 30-50 pF

- Stringent requirements for Front-End Electronics
 - Low power (<10 mW), low noise (<2000 e-), high radiation (200 Mrad, 10^{E16} N)
 - System on chip (digitization, processing...), high speed readout (5-10 Gb/s)
 - ~92,000 FE chips
- Baseline : charge + ToT [J. Kaplon CERN]
 - Charge readout 0-100 fC (0-50 MIP) 10 bits
 - Time over Threshold (0.1-10 pC) (40-2000 MIPs) : 12 bits
 - In addition : **timing information to 50 ps accuracy**
 - Variants : more classical readout (bi-gain) or switched feedback [Omega]

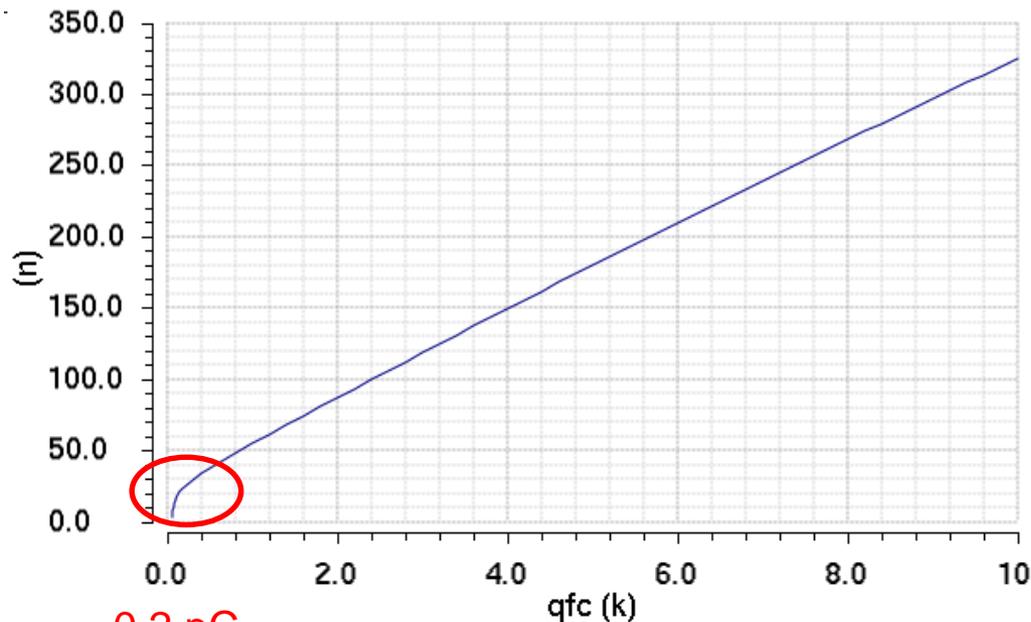


- key issues to be studied :

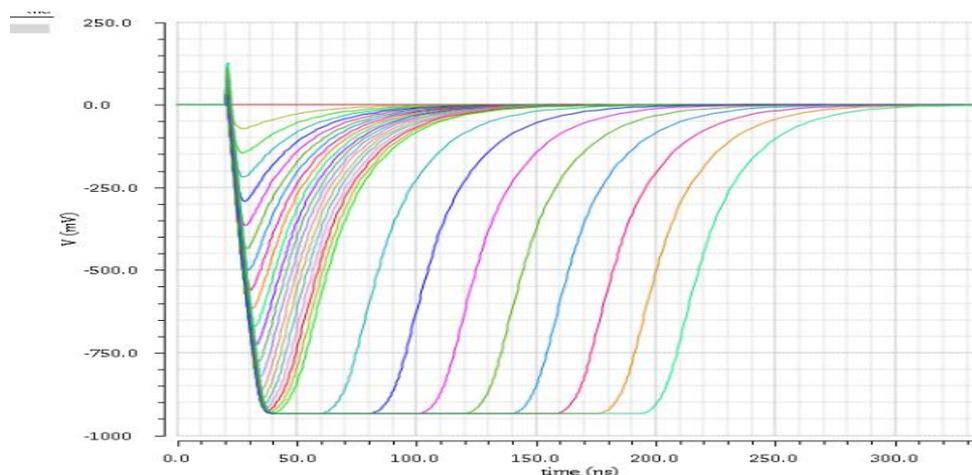
- Noise
- Resolution
- Stability
- Linearity
- Accuracy
- Calibration
- crosstalk
- Radiation
- Timing
- Systematic effects

- And also

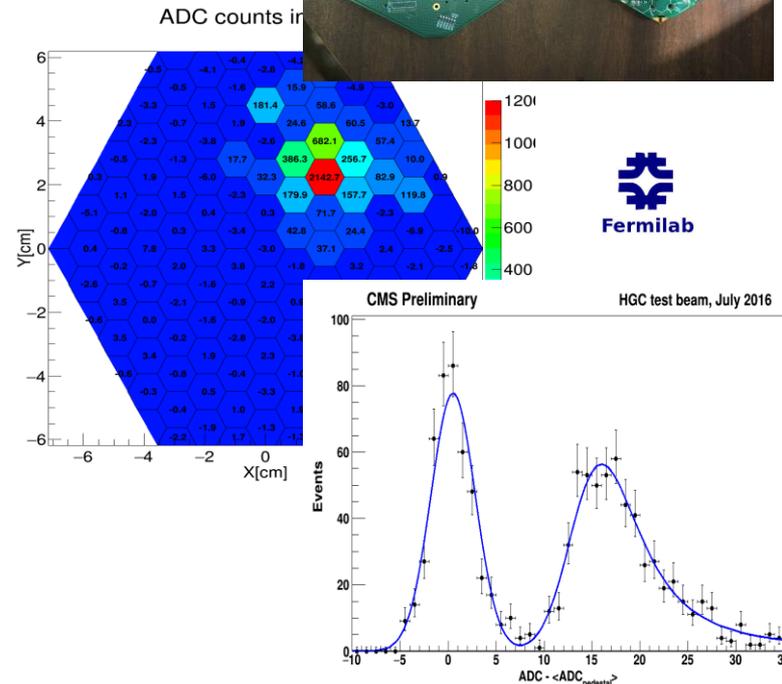
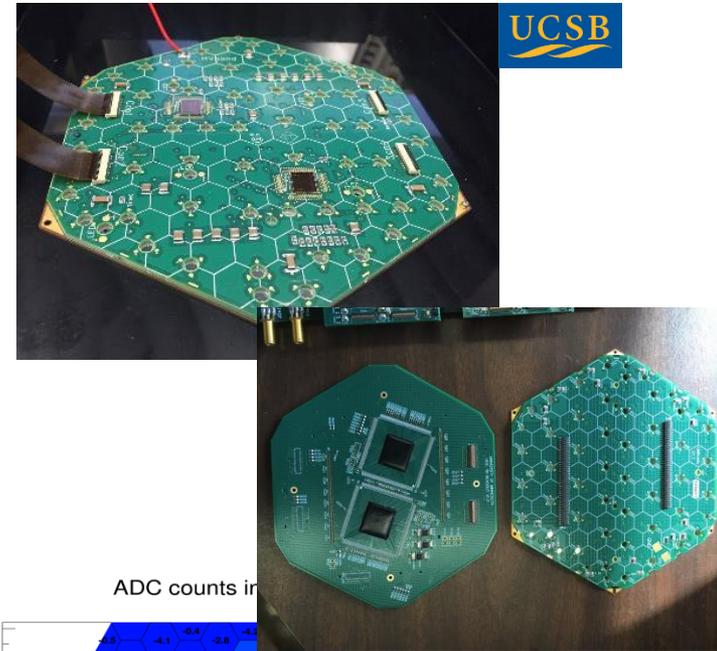
- 65/130 nm
- System issues
- Trigger path



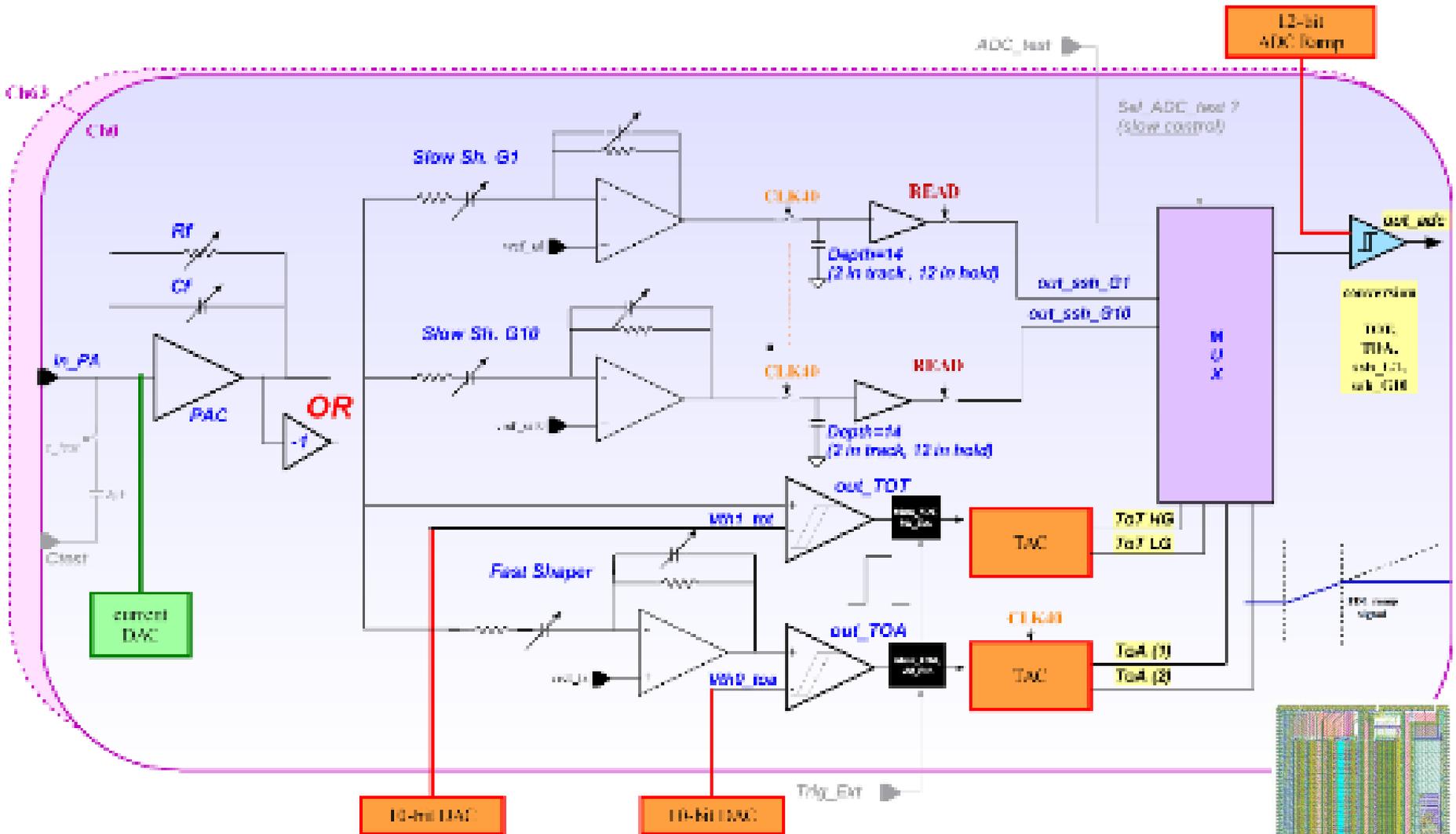
0.2 pC
~100 MIPS



- Testbeam electronics
 - Use SKIROC2 from CALICE to exercise system issues (low noise, large range)
 - Complex front-end boards designed at UCSB and FNAL and CERN
 - Evolutive readout designed at FNAL
- Development of **SKIROC2-CMS**
 - Optimized version for CMS test beams, pin to pin compatible
 - Dual polarity charge/current preamplifier
 - Faster slow shaper (25ns instead of 200ns)
 - SCA in roll mode (sampling of slow shapers @ 40MHz, depth = 300ns)
 - ToT for high input charge
 - TDC (TAC) for ToA (~20 ps binning, ~50ps jitter)
 - Will replace SKIROC2 on modules for **timing and ToT studies**



- 64 channels versatile Si calorimeter readout based on CALICE SKIROC2



Digital readout scheme

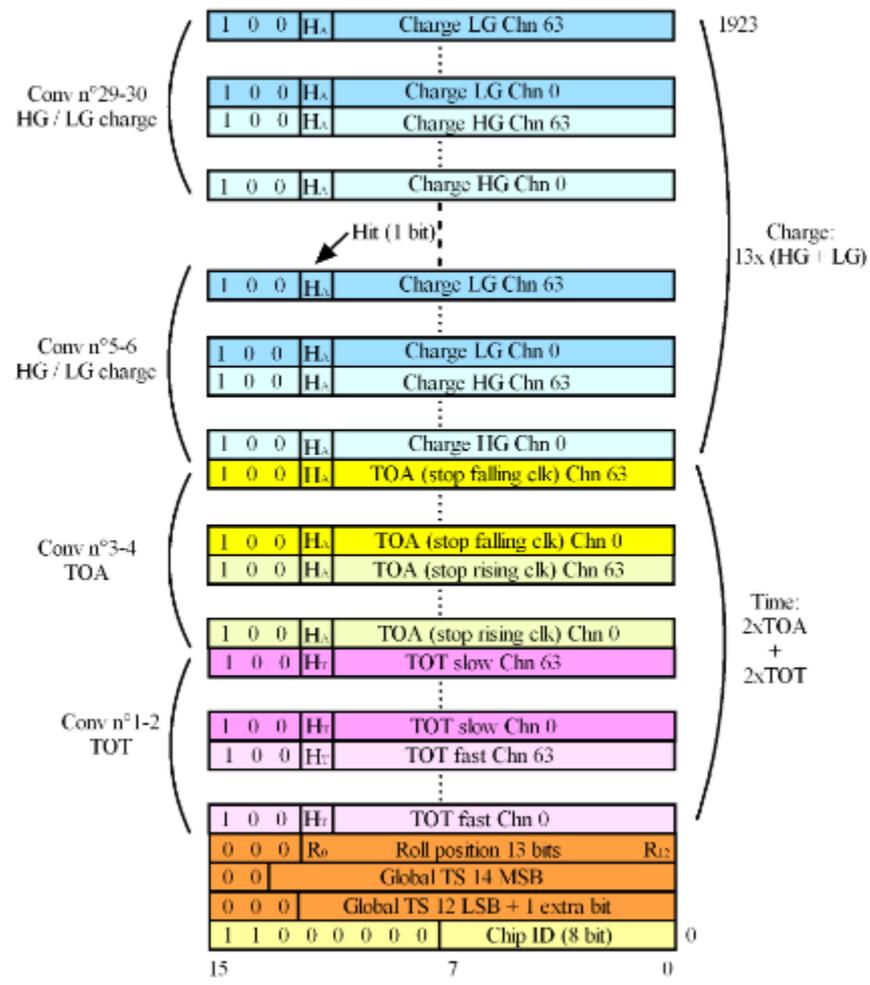
- Based on Calice chips readout scheme



- Roll mode @ 40MHz
- depth 12x25ns=300ns

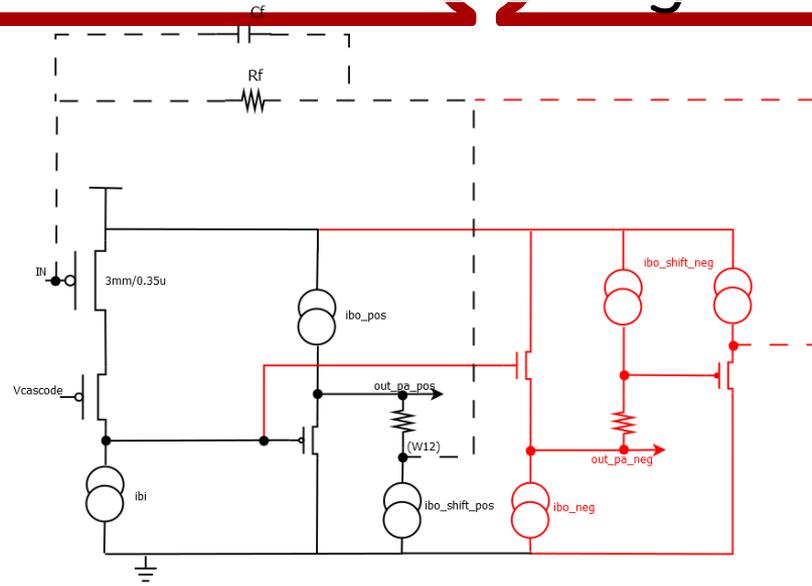
- 12-bit Wilkinson ADC, starts on external Trigger
- 2 ToT (fast & slow); 2 ToA; 2x13 HG & LG Charge
- Duration (worst case)= $2^{12} \times 25n \times 30 = 3 \text{ ms}$

- OC @ 5MHz (SK2) to LVDS @ 40MHz (SK2-CMS)
- Cst. $1924 \times 16 \times 25 = 770 \mu\text{s}$



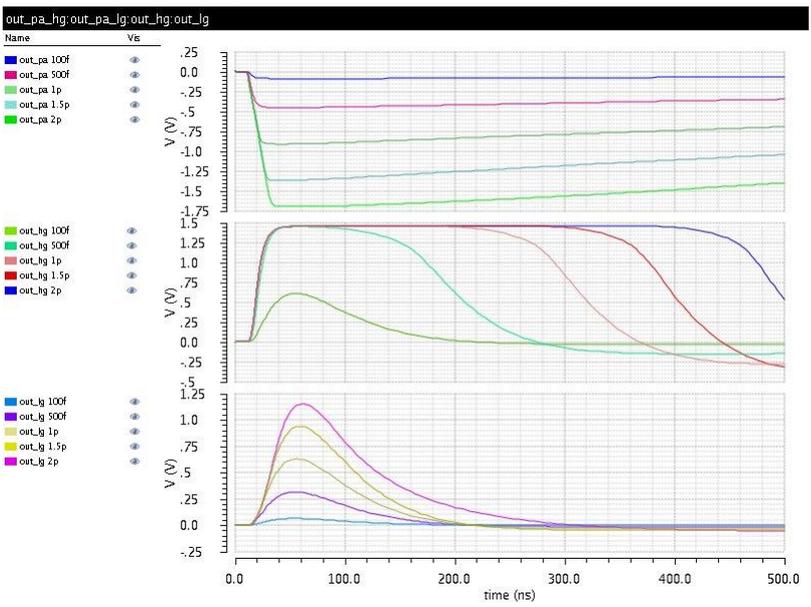
Preamp architecture

- PMOS input $I_d=1$ mA, direct cascode
- Variable R_f 20k-2M, $C_f=0.06$ -4p (4 bits)
- Level shifter for negative polarity

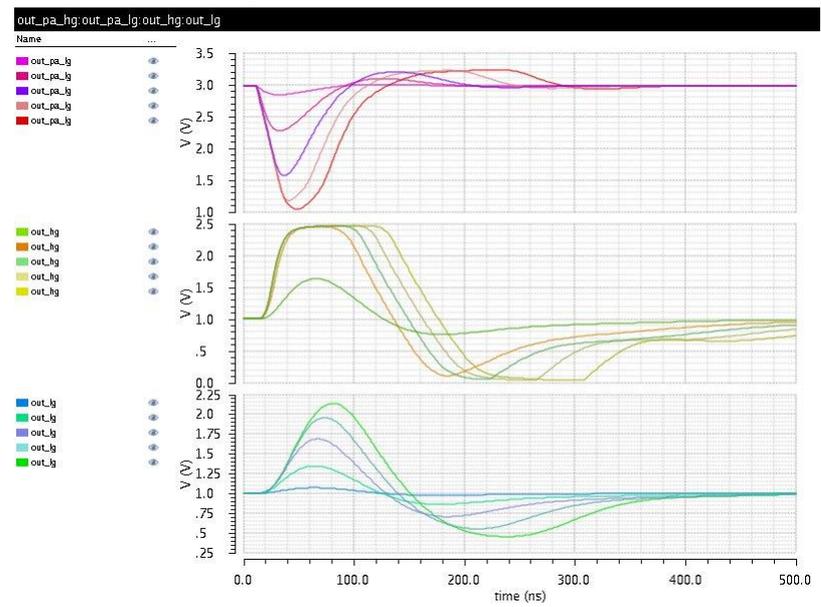


ENC	$R_f=1M, C_f=1pF$	$R_f=20k, C_f=500fF$
Positive input	0,2fC (1250 e-)	0,25fC (1560 e-)
Negative input	0,23fC (1440 e-)	0,3fC (1875 e-)

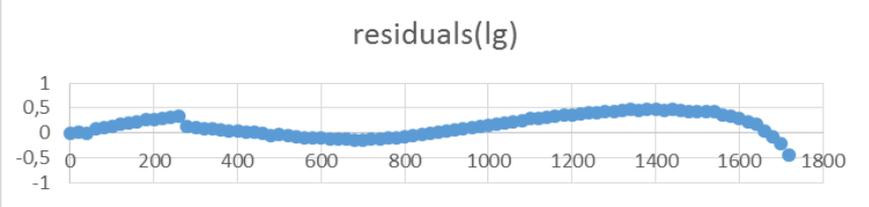
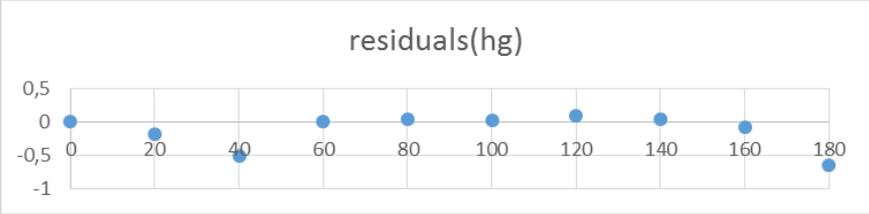
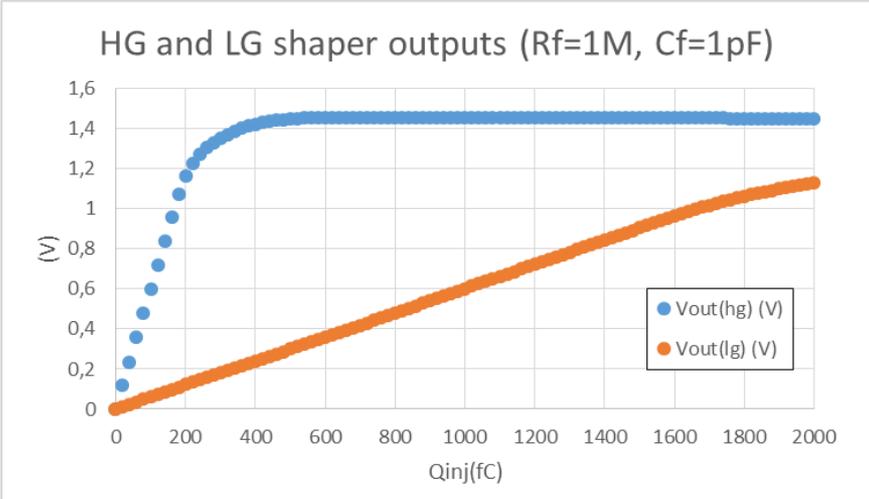
Preamp: $R_f=1M, C_f=1pF$



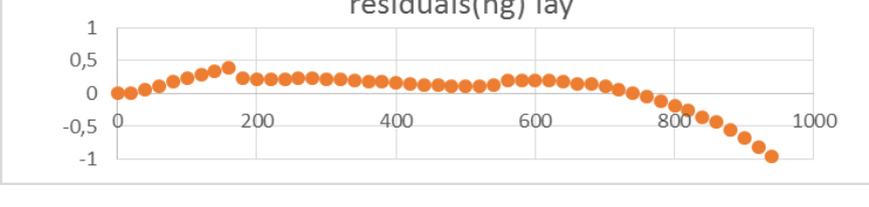
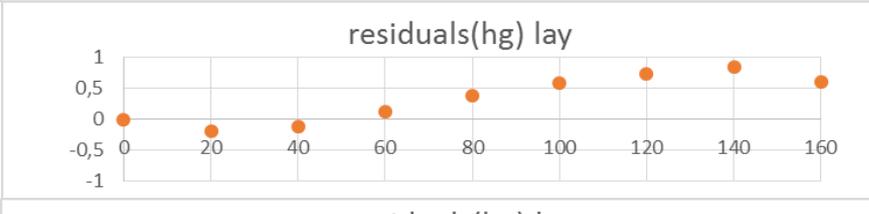
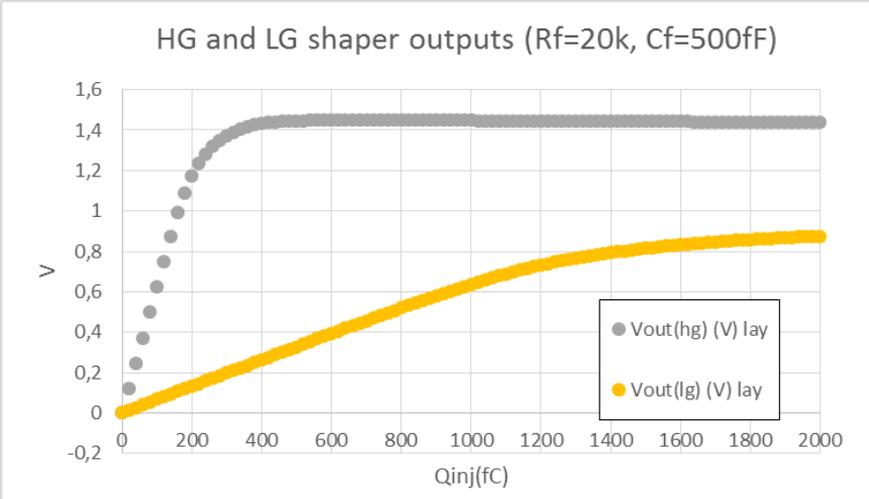
Preamp: $R_f=20k, C_f=500fF$



Preamp: $R_f=1M$, $C_f=1pF$



Preamp: $R_f=20k$, $C_f=500fF$



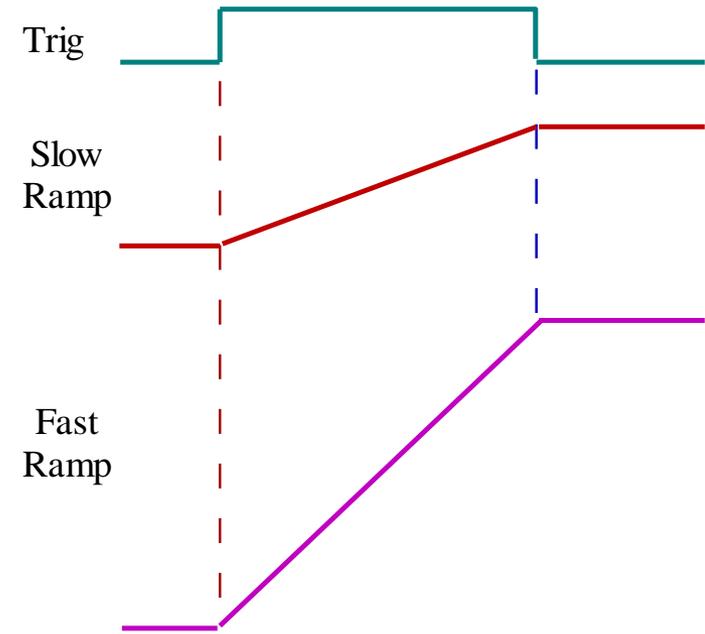
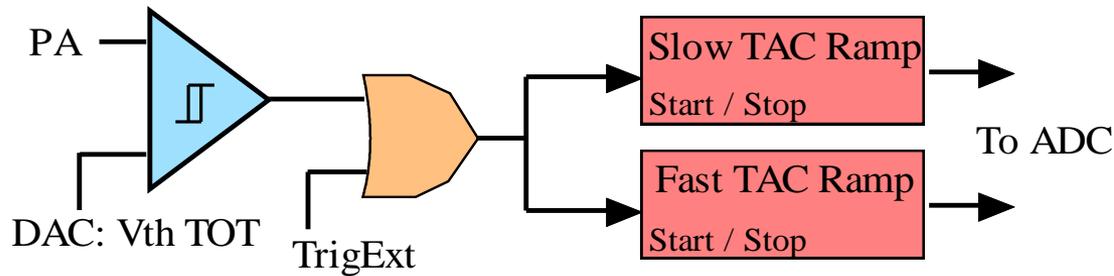
- HG linearity: from 0 to 180 fC
- LG linearity: from 0 to 1700 fC

- HG linearity: from 0 to 160 fC
- LG linearity: from 0 to 950 fC

Time over Threshold principle (TOT)

TOT based on a Time to Amplitude Converter (TAC):

- ❑ 2 analog ramp / channel
- ❑ Slow ramp to validate TOT mode (~0-500 ns)
- ❑ Fast ramp to characterize non-linear region (~0-50 ns)
- ❑ 1 global TrigExt available to calibrate TOT



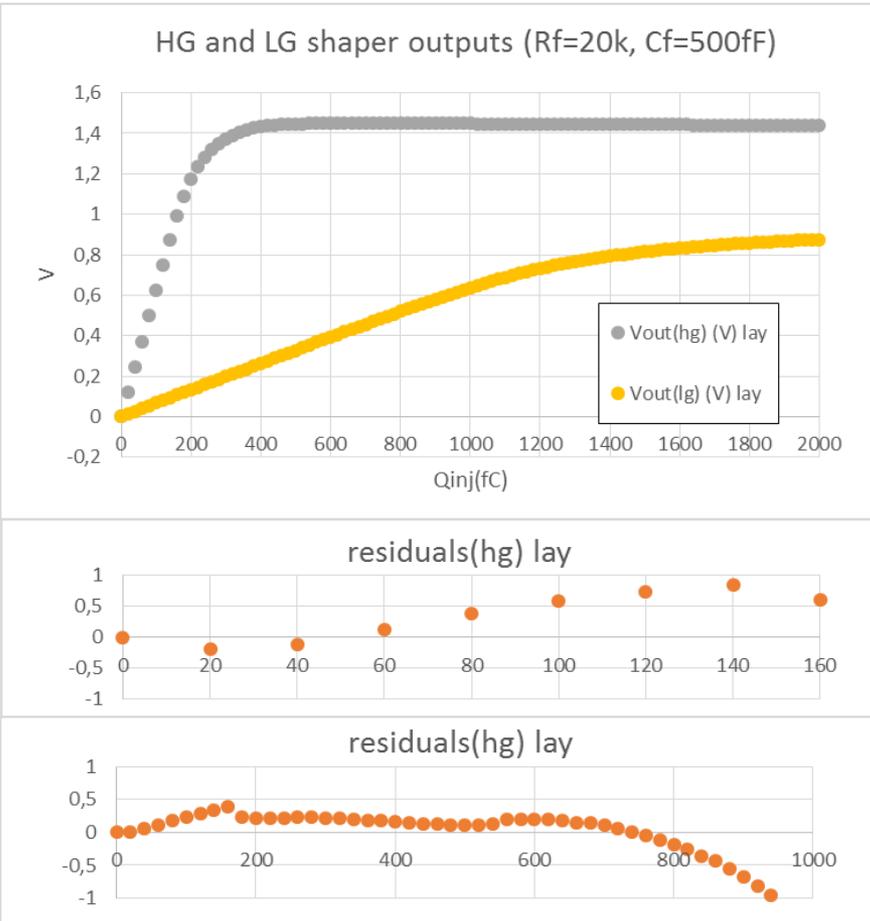
Channel with TOT data are marked with Hit bit

Relevant data in memory mapping:

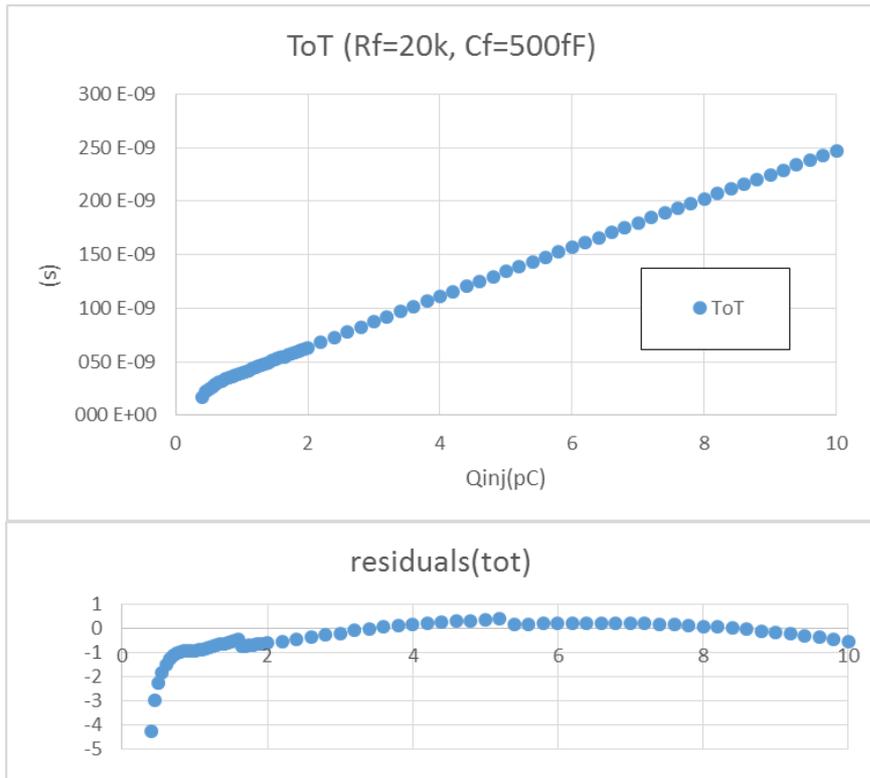
- ❑ Digitized TAC ramp (fast / slow)
- ❑ Hit bit (H_T)

1	0	0	H_T	TOT slow Chn 0
1	0	0	H_T	TOT fast Chn 0

Preamp: $R_f=20k$, $C_f=500fF$



Preamp: $R_f=20k$, $C_f=500fF$

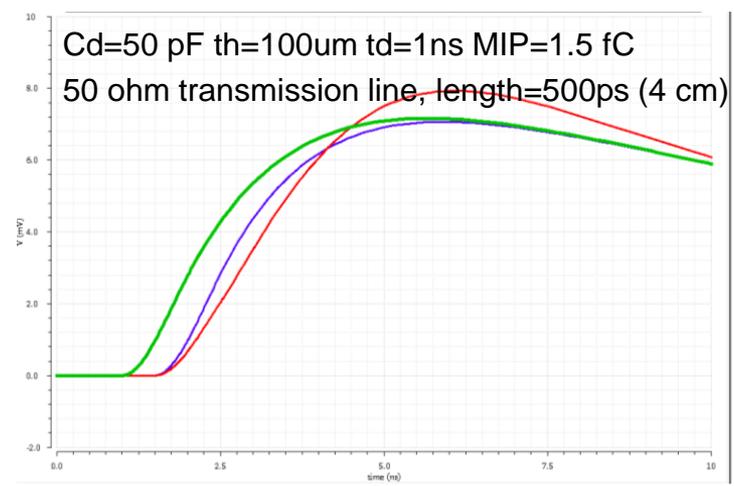
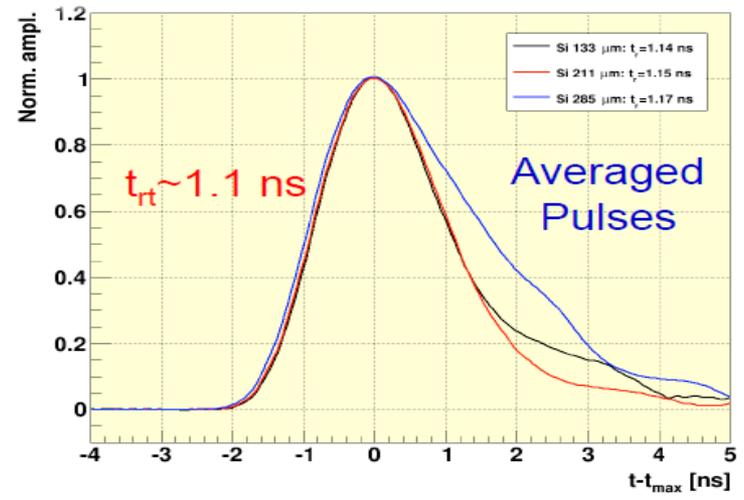
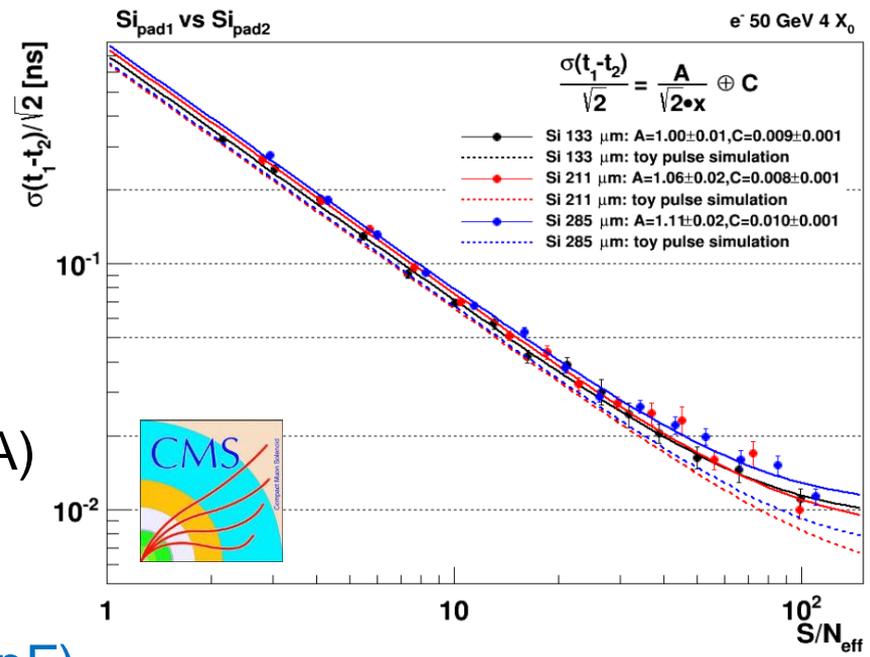


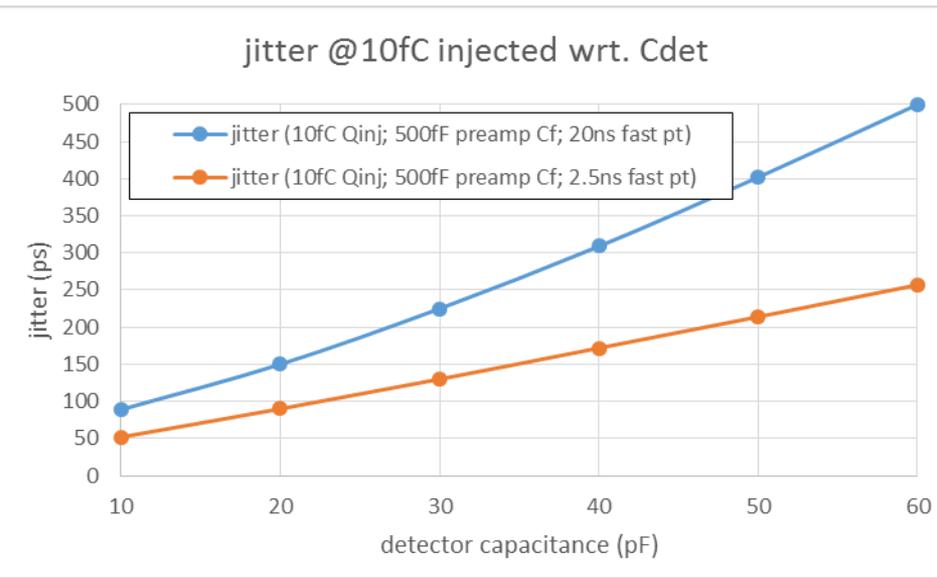
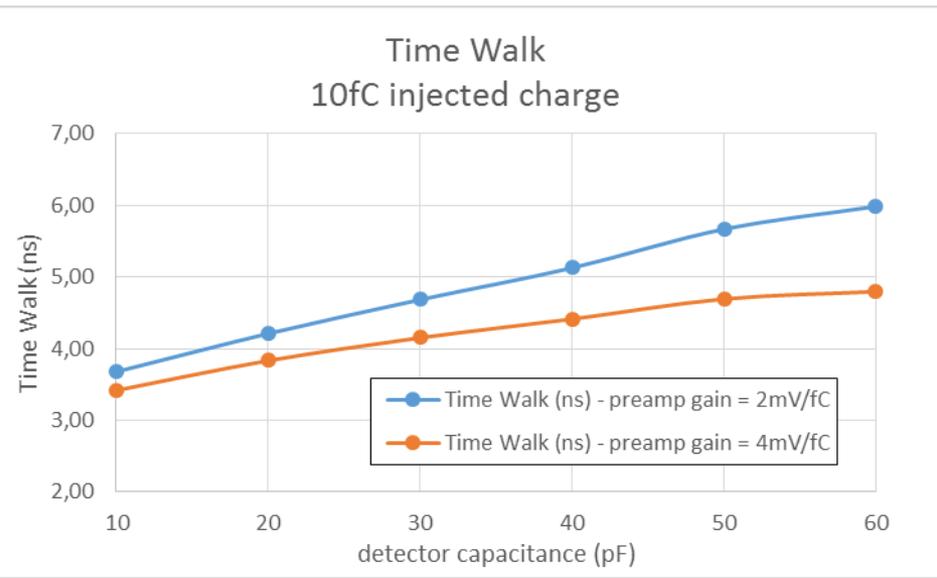
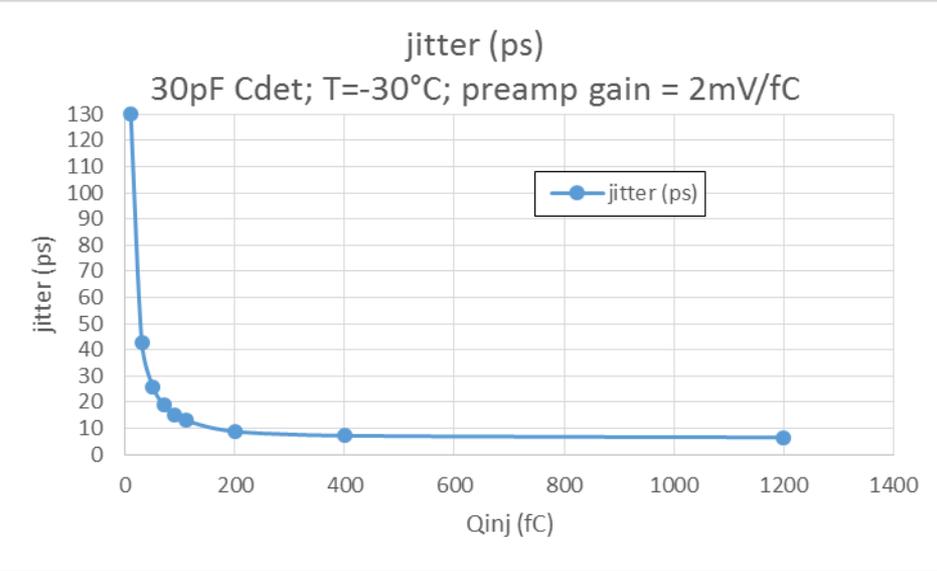
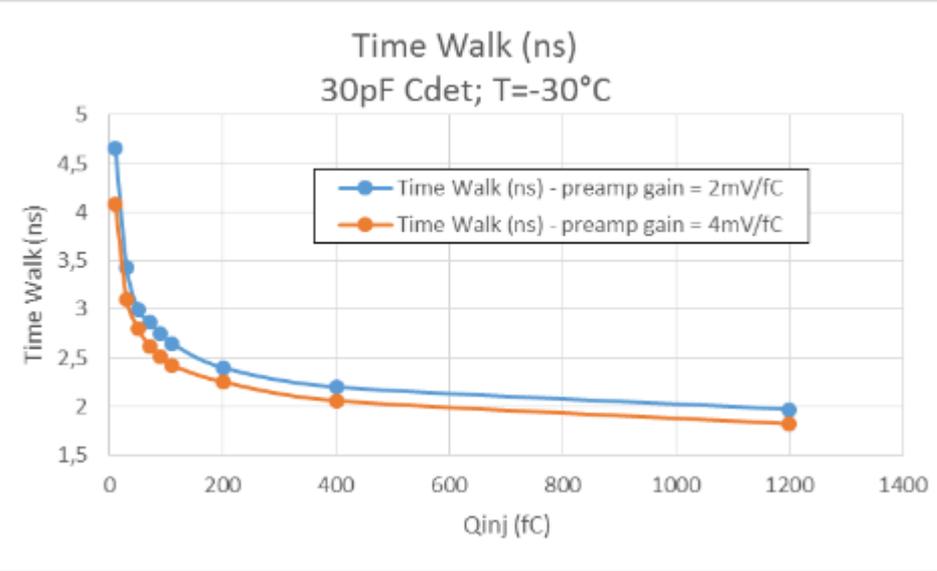
- Threshold @ 700 fC
- ToT linearity: from 800 fC to 10 pC

- Threshold @ 450 fC
- ToT linearity: from 1,7 pC to 10 pC

Timing studies

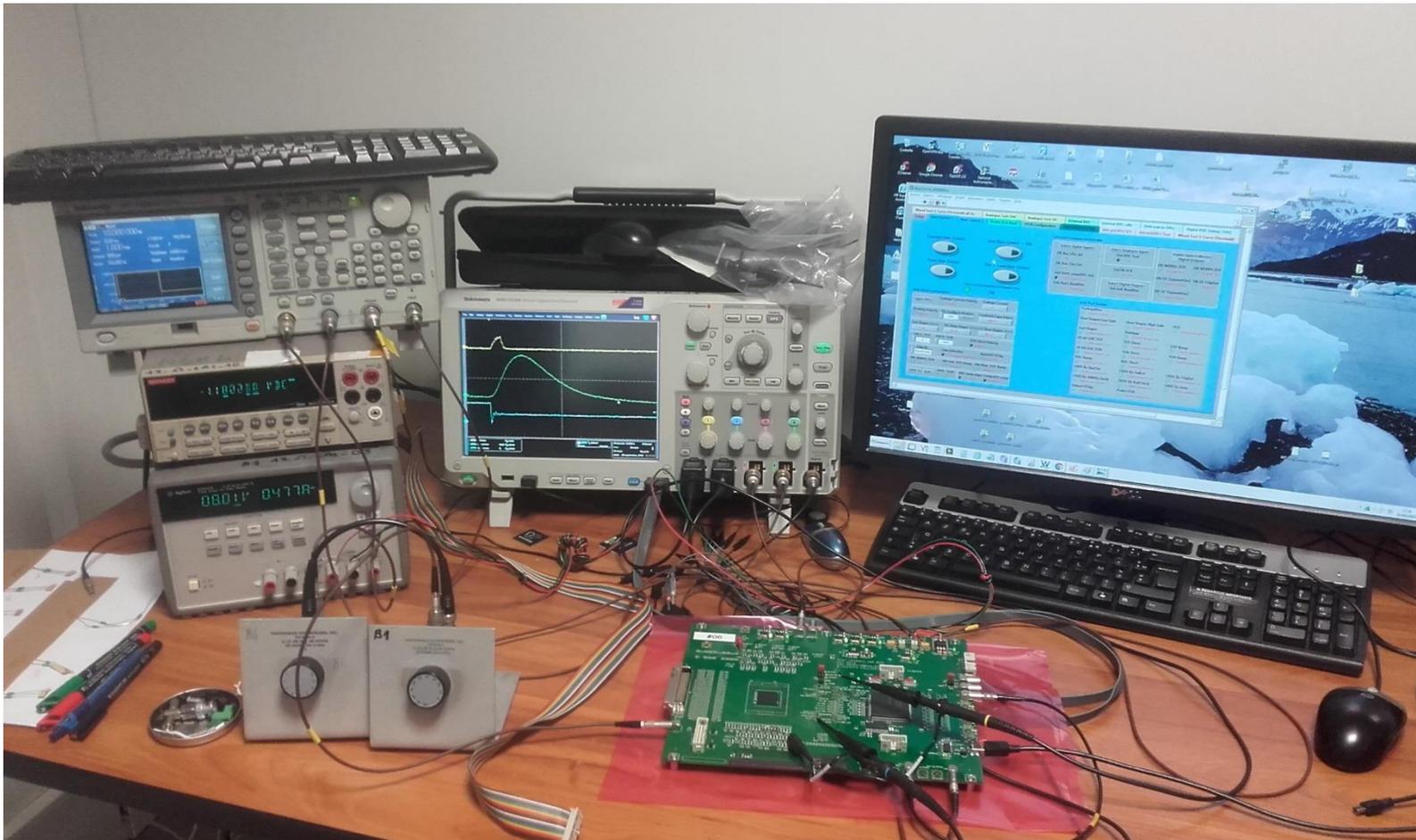
- Timing tests *[M Mannelli et al. ACES2016]*
 - 700ps/(S/N) (+) 20 ps
 - But 2 GHz BB amps
 - 5 Gs/s digitization
- Theory : $\sigma_t^J \approx \alpha \cdot C_d \sqrt{\frac{t_d}{g_m}}$
- But different readout electronics (CSA)
 - Different S/N, Reflections in PCB ?
 - Time walk corrections
- Expect ~ 3-4 ns/fC (+) 50 ps (Cd=50pF)







- Chips packaged in BGA for testboards
- Tests carried out at Imperial College, Univ Split and OMEGA

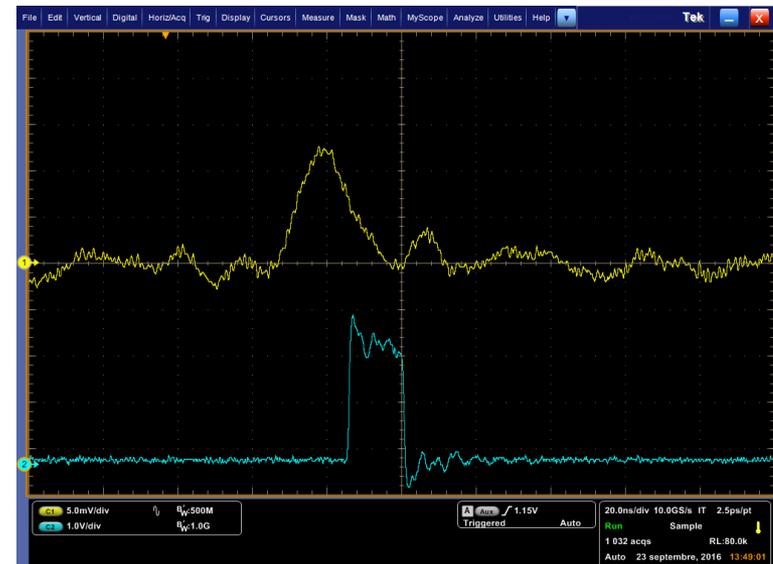
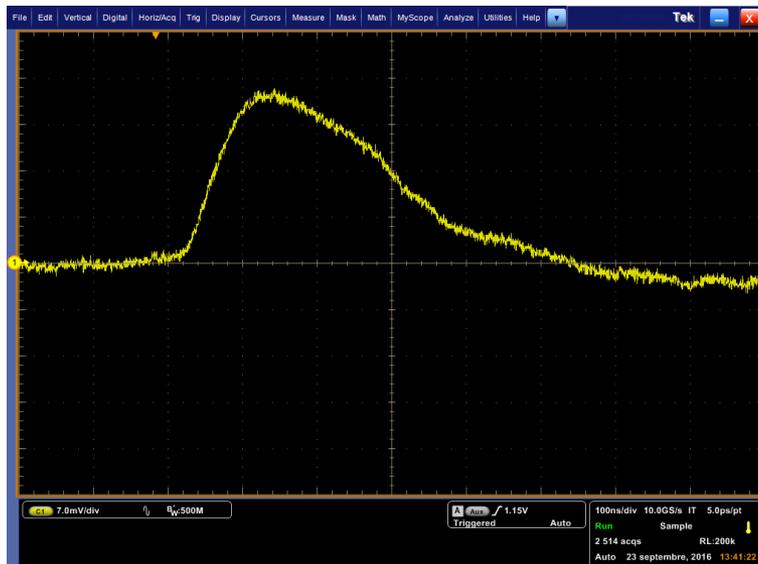
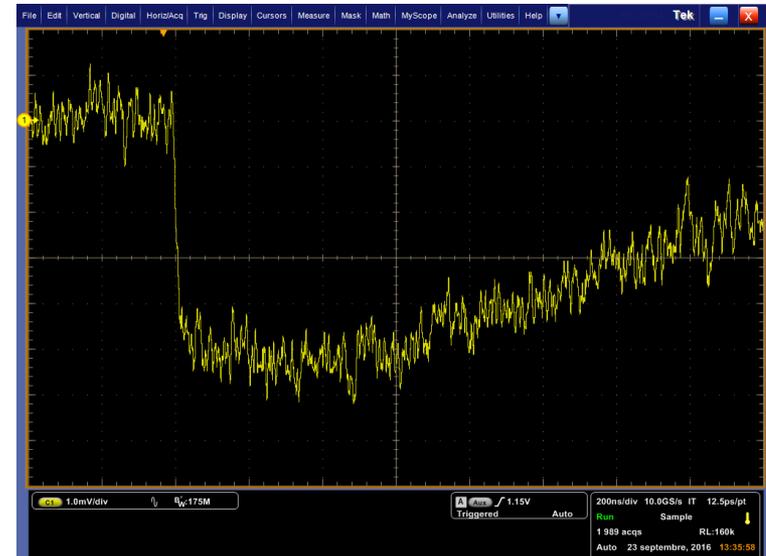


- 40 MHz circular analog memory. 13 cells in store and 2 in track
- Allows ~300 ns trigger latency

The screenshot displays the SCA control software interface with the following sections:

- Navigation Tabs:** Setup, Slow Control 1, Slow Control 2, Probe, SCA Read, FPGA Configuration, Info SKIROC2-CMS, Info pcb1011 I/O, Info pcb1011 Test, Mixed Test: S-Curve (Threshold).
- Sub-Tabs:** Mixed Test: S-Curve (Threshold) all Ch., Analogue Test: DAC, Analogue Test: DC, External ADC, Internal ADC calib, Hold scan w. DAQ, Digital ASIC Debug / DAQ.
- Step by Step DAQ:** Includes buttons for Reset ASIC Digital, Start Acquisition, Start ReadOut1, Start ReadOut2, and progress indicators for ChipSat, End ReadOut1, and End ReadOut2.
- Automatic DAQ:** Includes buttons for Automatic DAQ, Start Acq. Sequence, and a note that ChipSatb must be enabled. It also shows Nb of Acquisitions set to 1 and an Overflow Correction indicator.
- Data Analysis:** Includes a Clean DAQ data folder button, Channel selection (set to 1), Column selection (set to 4), and an Analyze saved data now! button.
- Status and Configuration:** Frame received OK? (OK), Nb of bits read in ASIC RAM (30784), Data Error (CRC) (OK), Chip ID (01101101), Global TS (80), Used Fast Clock (FPGA 50.52MHz or 40MHz Clock), and Fast clock freq (40MHz).
- Data Plots:** Two plots showing ADC output (12 bits) vs Analogue Memory. The HG Ch waveform shows a peak at memory cell 3, and the LG Ch waveform shows a peak at memory cell 3.

- 3 fC test pulse injection ~ 1 MIP
- Preamp $C_f = 0.5$ pF $R_f = 2.5$ M Ω $C_d = 0$
 - $V_{out} = 5$ mV $N = 0.4$ mV
- HG shaper $\tau = 20$ ns
 - $V_{out} = 15$ mV $N = 1.2$ mV
- Fast shaper $\tau = 5$ ns
 - $V_{out} = 12$ mV $N = 1.4$ mV



- Charge sensitive configuration : $R_f = 2.5 \text{ M}\Omega$ $C_f = 0.5 \text{ pF}$
- Hi Gain / Lo Gain positive/negative configurations

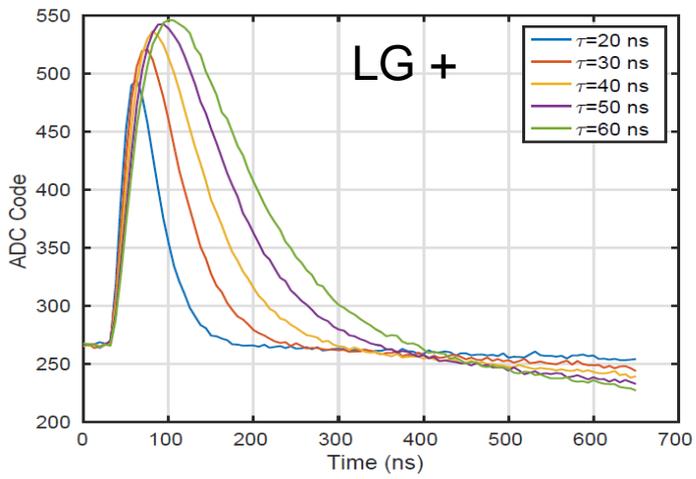


Figure 29: Shaper response for different tau, Low-gain, positive polarity

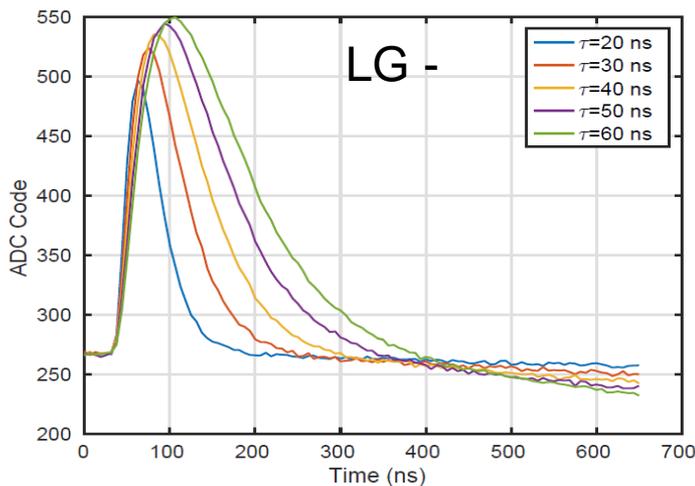


Figure 31: Shaper response for different tau, Low-gain, negative polarity

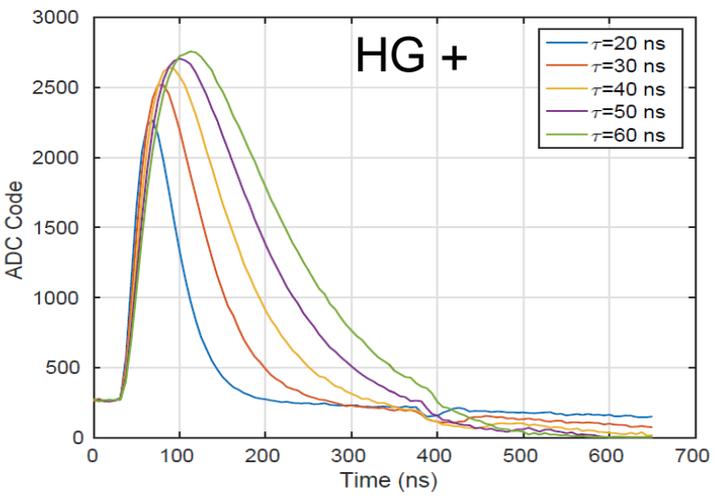


Figure 30: Shaper response for different tau, High-gain, positive polarity

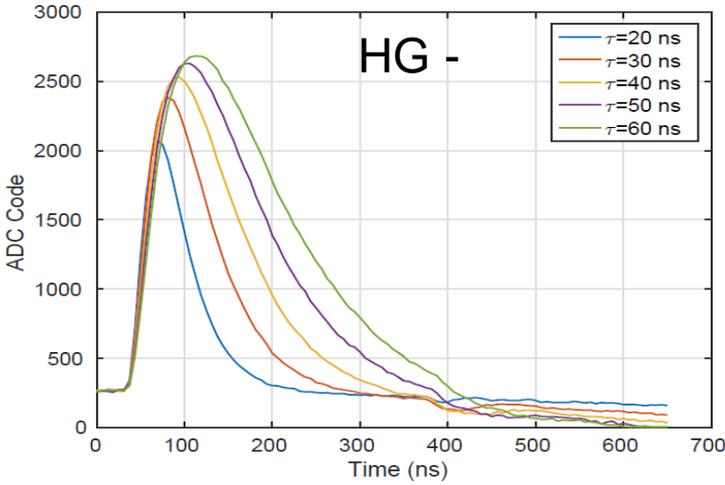


Figure 32: Shaper response for different tau, High-gain, negative polarity

- Linearity < 1%, temperature sensitivity ~0.1%/K

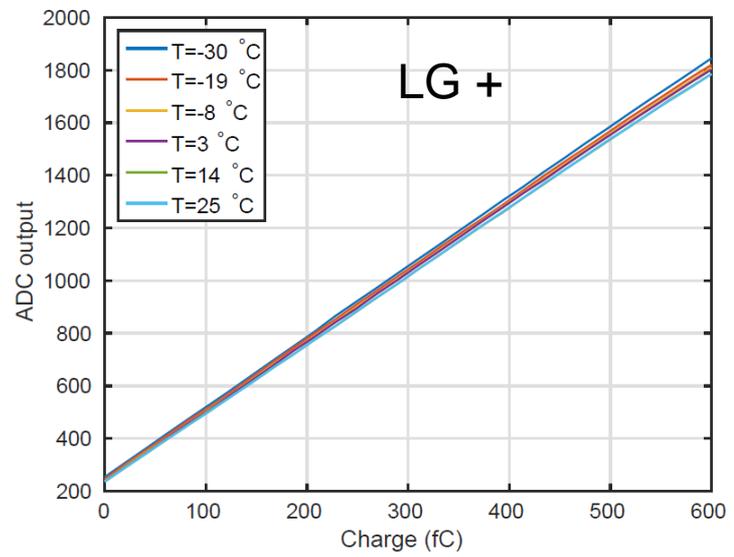
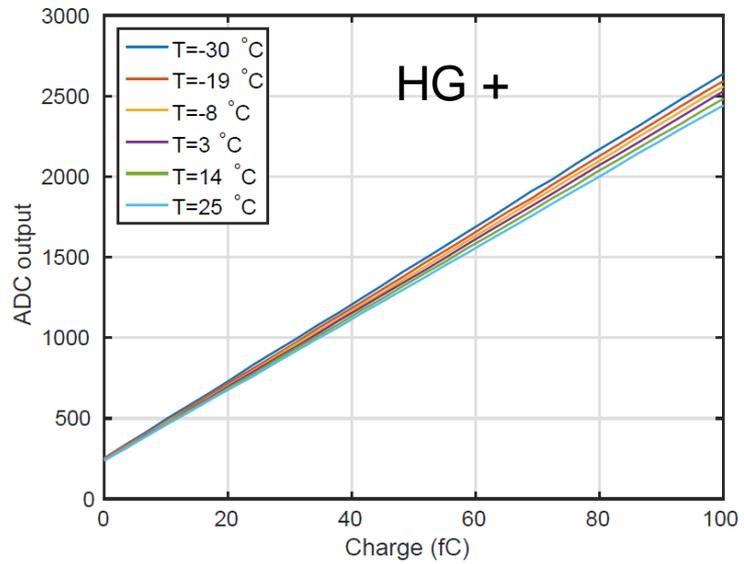
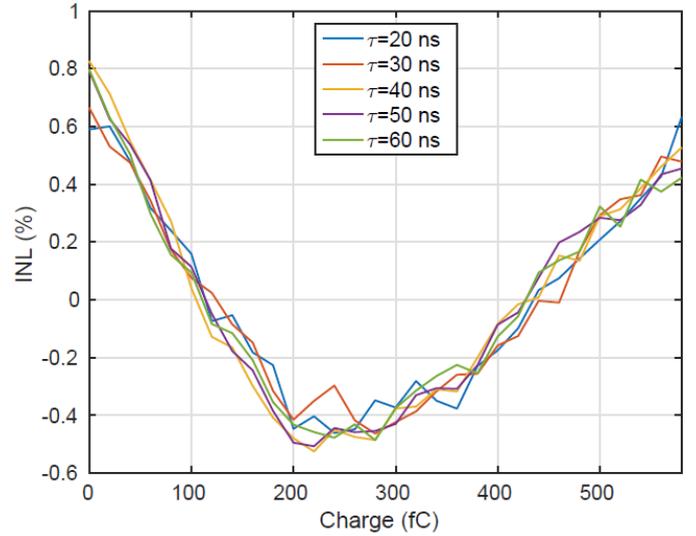
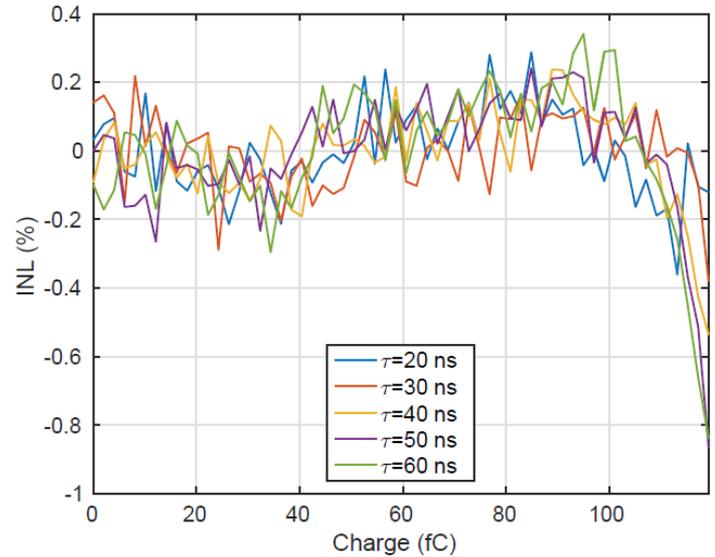


Figure 3: High-gain transfer function for different T, positive polarity, $\tau = 40ns$

Fig



ns

- Dispersion $\sim 0.5\%$ rms stability : $0.1\%/K$

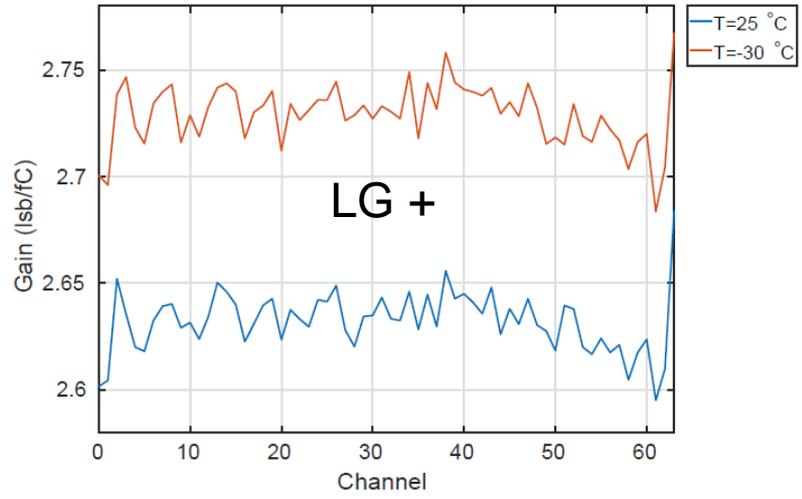


Figure 1: Low-gain gain of each channel, $\sigma_{25}=0.014$ (lsb/fC), $\sigma_{-30}=0.014$ (lsb/fC)

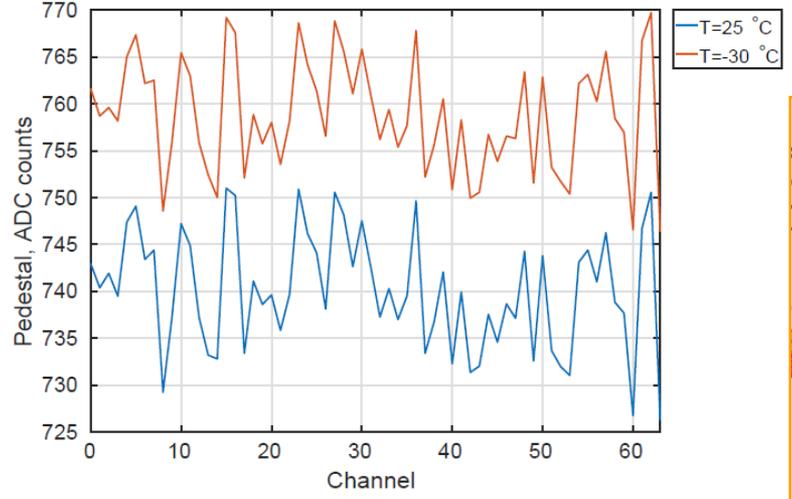


Figure 2: Low-gain pedestal of each channel in ADC units, $\sigma_{25}=6.3$ (lsb), $\sigma_{-30}=6.0$ (lsb)

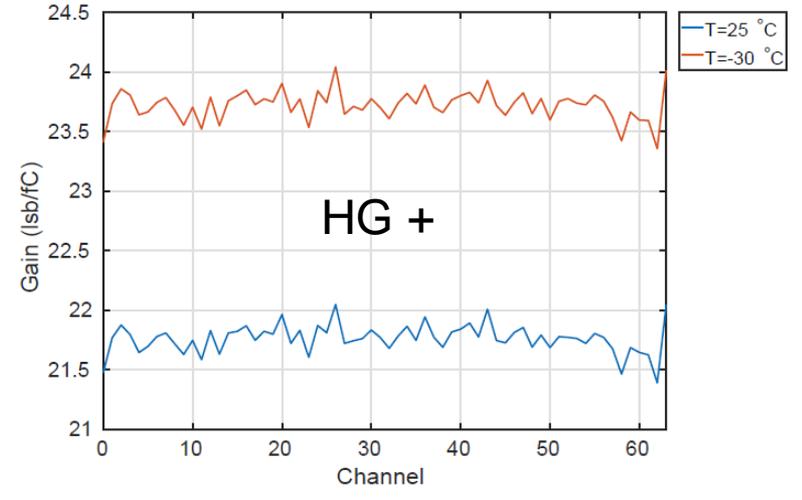


Figure 4: High-gain gain of each channel, $\sigma_{25}=0.120$ (lsb/fC), $\sigma_{-30}=0.126$ (lsb/fC)

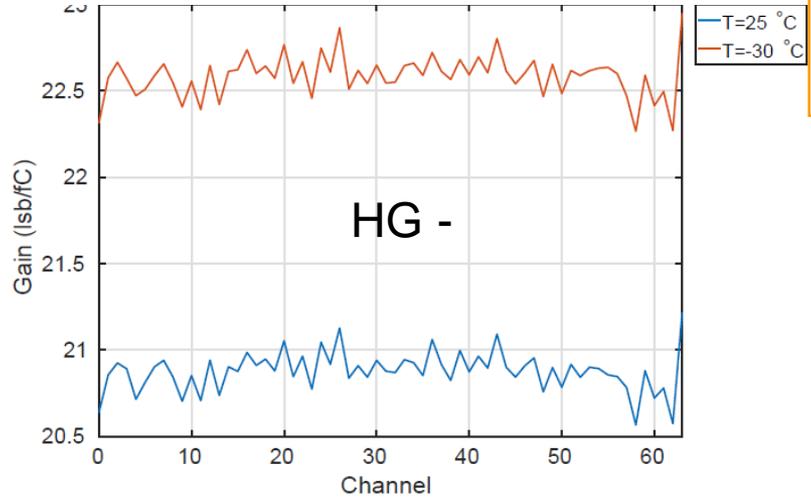


Figure 16: High-gain gain of each channel, $\sigma_{25}=0.116$ (lsb/fC), $\sigma_{-30}=0.122$ (lsb/fC)

- $C_d = 47$ pF, positive and negative preamps
- Shaping time = 20-60 ns
- ENC = 0.3-0.4 fC = 2000-2500 e⁻
- Series-noise dominated, slightly worse for negative (as expected)

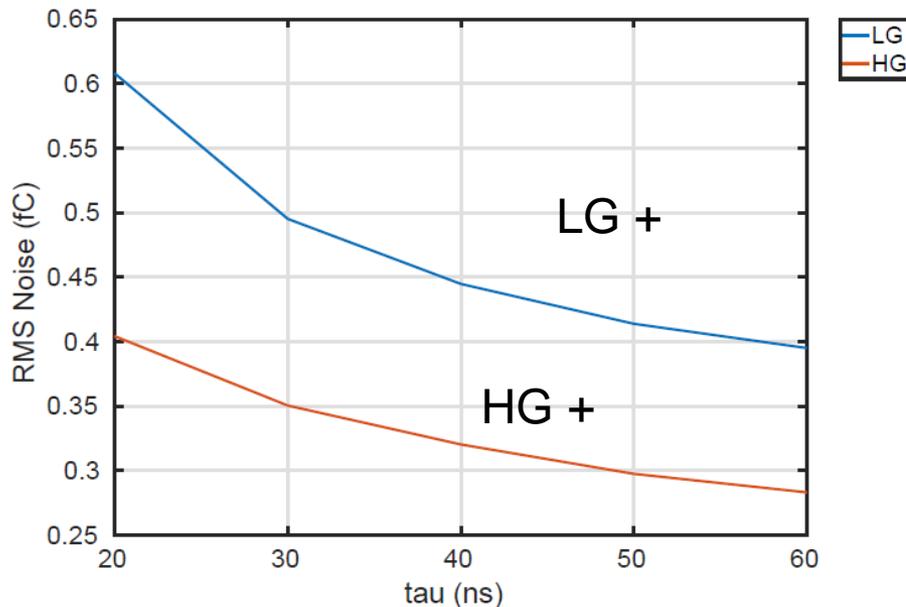


Figure 17: Noise vs shaper setting scaled based on Fig. 5

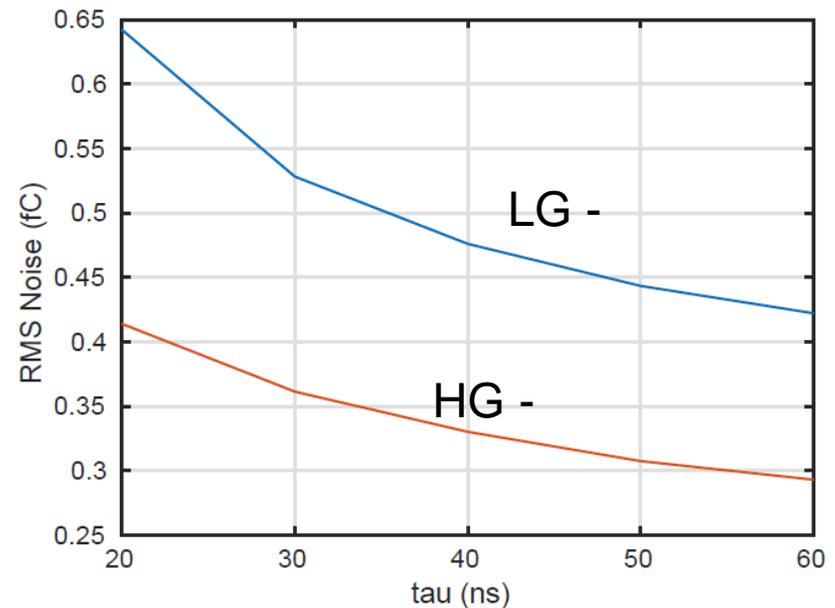
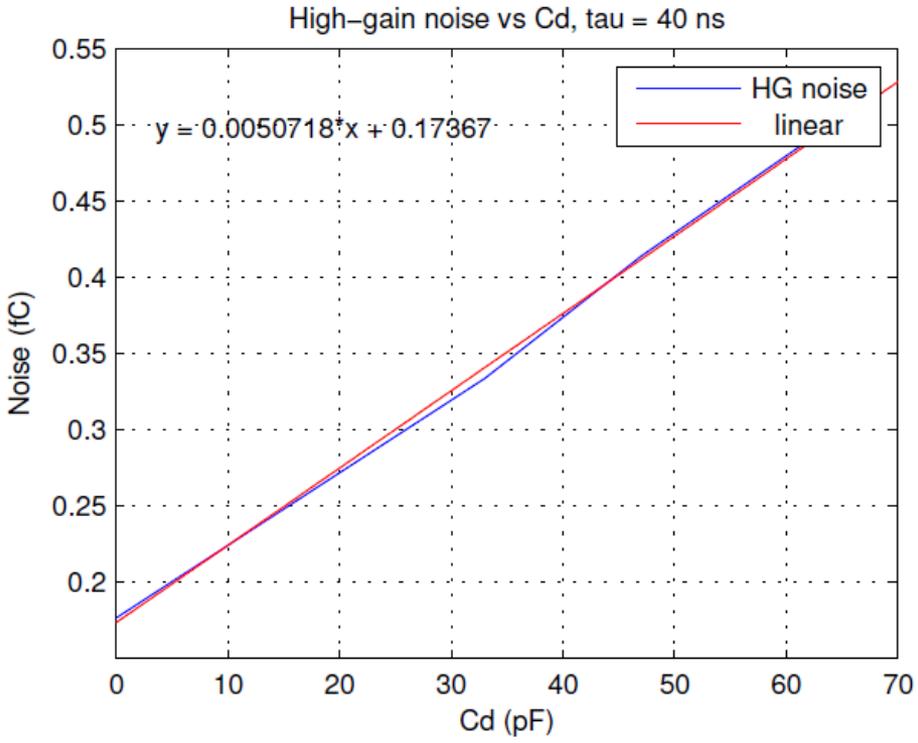


Figure 27: Noise vs shaper setting scaled based on Fig. 11

Noise vs capacitance

- Linear fit of series noise gives $e_n = 1.0 \text{ nV}/\sqrt{\text{Hz}}$
- Parasitic capacitance : $C_a = 34 \text{ pF}$ (10 pF chip 20 pF board)



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Figure 8: High-gain noise vs Cd, positive polarity, $\tau = 40 \text{ ns}$. Least-squares linear fit: $y = 0.17367 + 50.718 \times 10^{-3}x$ (fC, pF), $y = 0$ yields $C = 34 \text{ pF}$.

Noise autocorrelation function

- Series noise dominated at fast shaping
- Significant supply noise at slow shaping
- Removed with additional v_{DDA} filtering

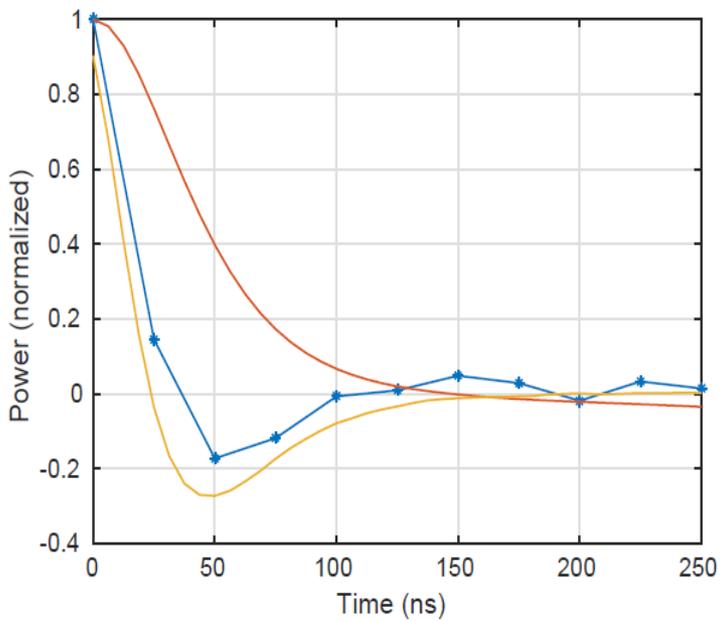


Figure 3: Normalized autocorrelation between bins, High-gain, $\tau=20$ ns.

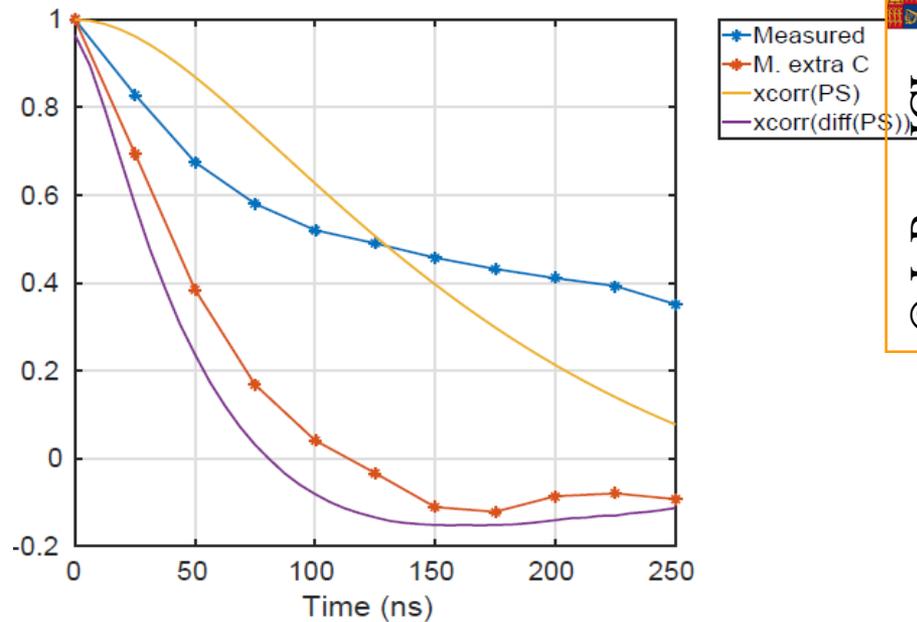


Figure 13: Normalized autocorrelation between bins, High-gain, $\tau=70$ ns.

Imperial College London

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Coherent and incoherent noise

- Using direct and alternate sums (DS and AS) on n channels (n=64)
- Incoherent noise $IN=AS / \sqrt{n}$
- Coherent noise : $CN = \sqrt{DS^2 - AS^2} / n$
- Coherent noise fraction : $CNF = CN / IN \sim 10\%$ at fast shaping.
- Measurement after v_{DDA} decoupling

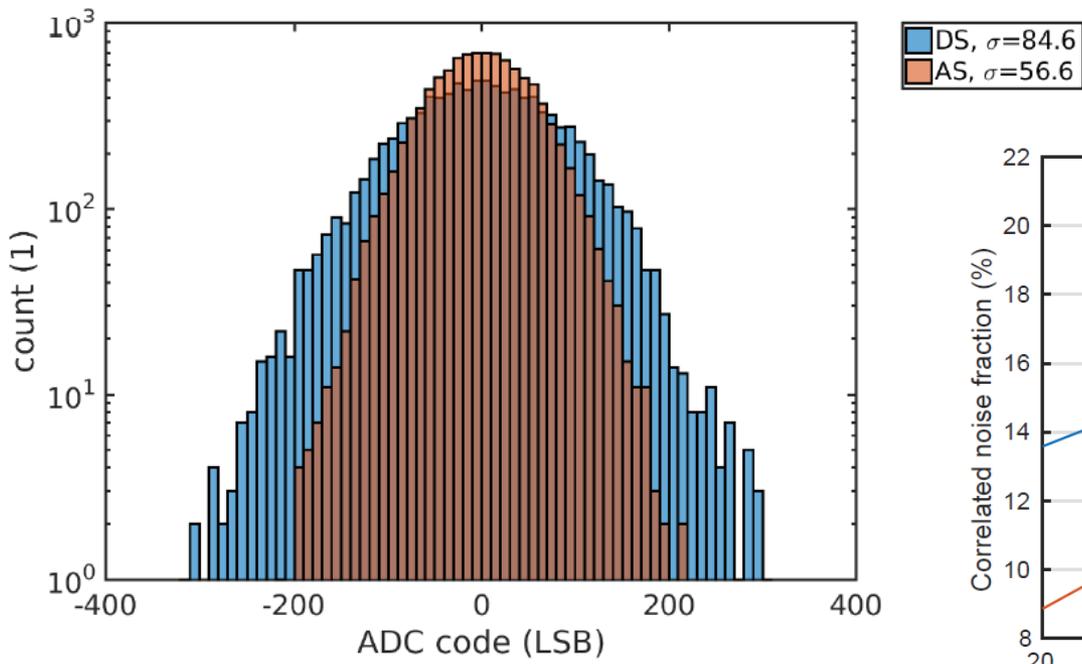


Figure 18: Histogram of direct and alternating sums, $\tau=40$ ns, High gain

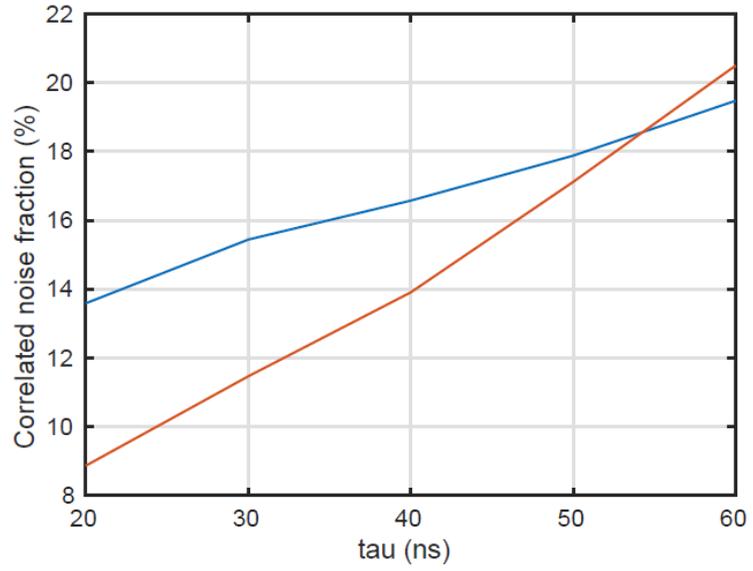


Figure 22: Correlated noise fraction (correlated/white)



- Current sensitive configuration : $R_f = 20\text{ k}\Omega$ $C_f = 0.5\text{ pF}$
- Hi Gain / Lo Gain positive/negative

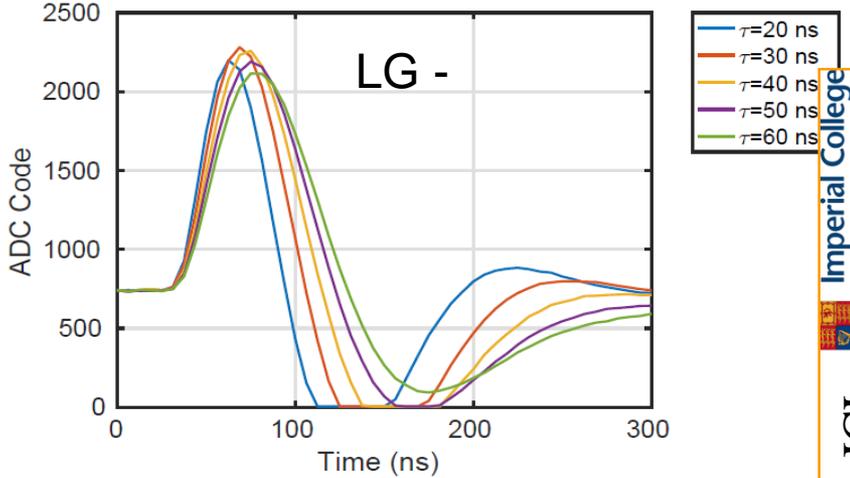
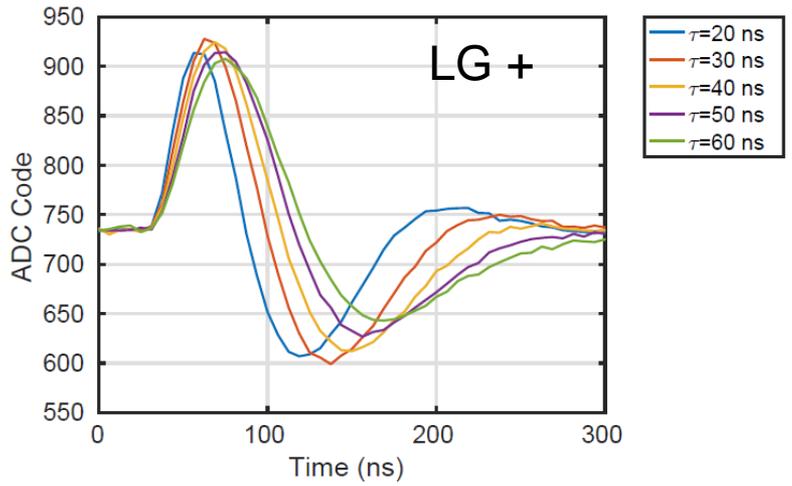


Figure 33: Shaper response for different tau, Low-gain, positive polarity

Figure 34: Shaper response for different tau, High-gain, positive polarity

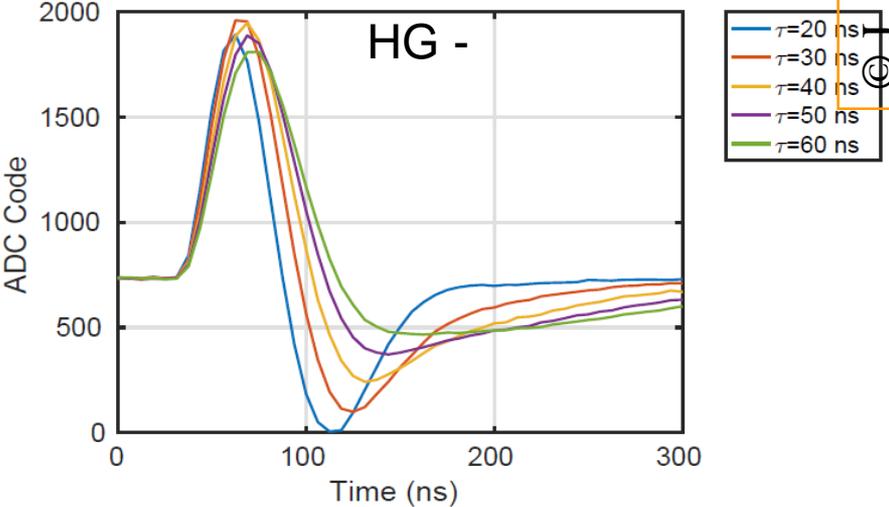
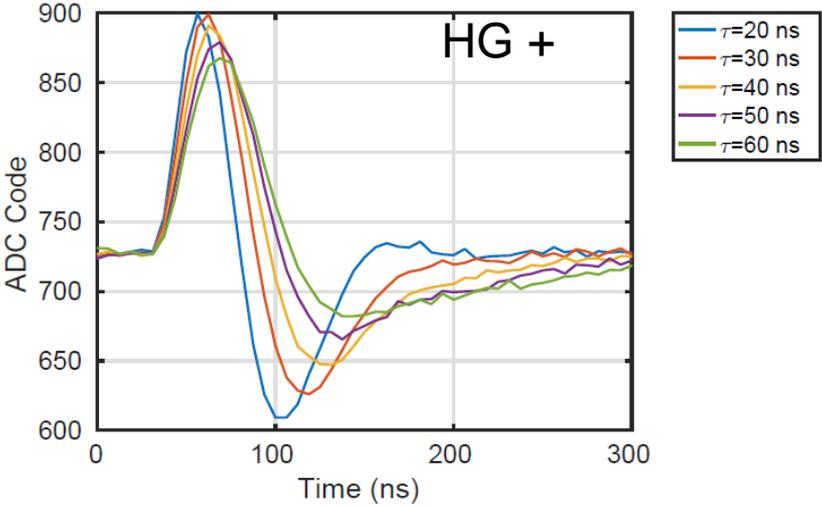


Figure 35: Shaper response for different tau, Low-gain, negative polarity

Figure 36: Shaper response for different tau, High-gain, negative polarity

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Trigger sensitivity for ToT

- discriminator at preamp output
- Low Threshold 30 fC high threshold 100 fC
- ~ 0.7 DACU / fC
- Dispersion ~ 5 fC

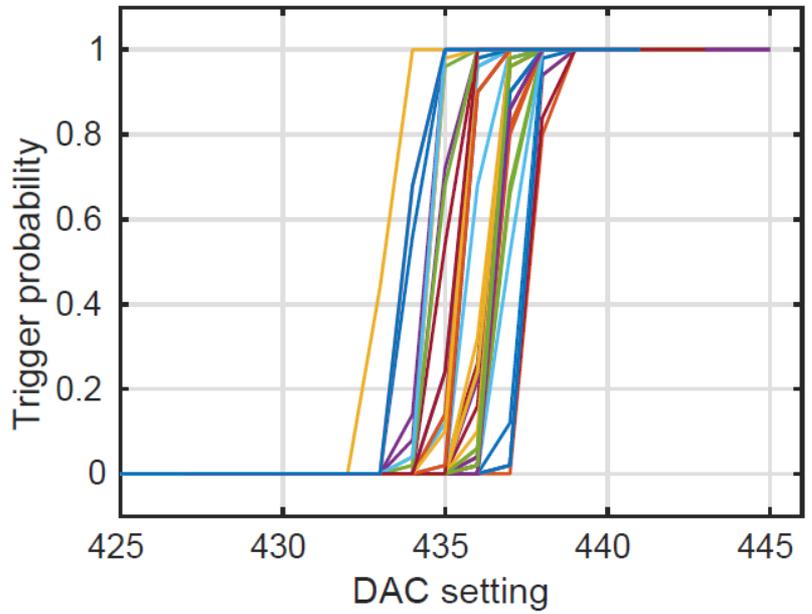


Figure 10: TOT S-curves at 10 fC

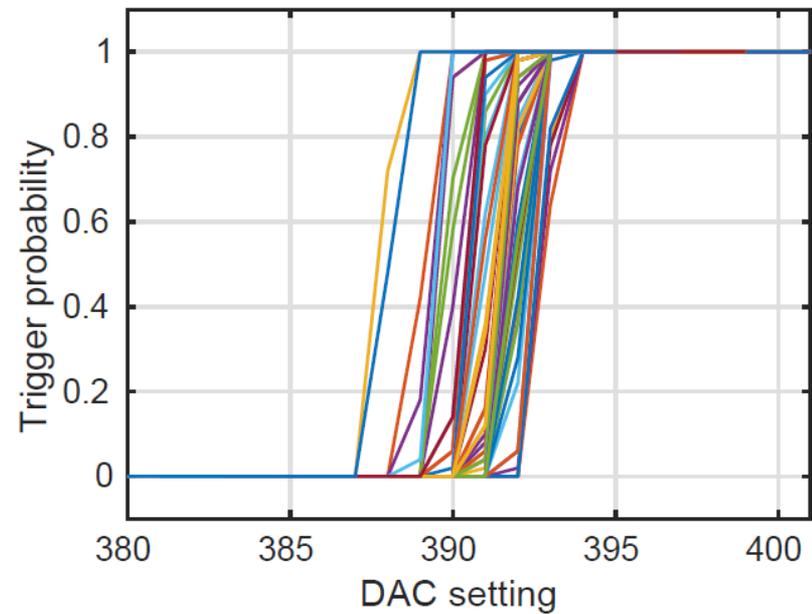
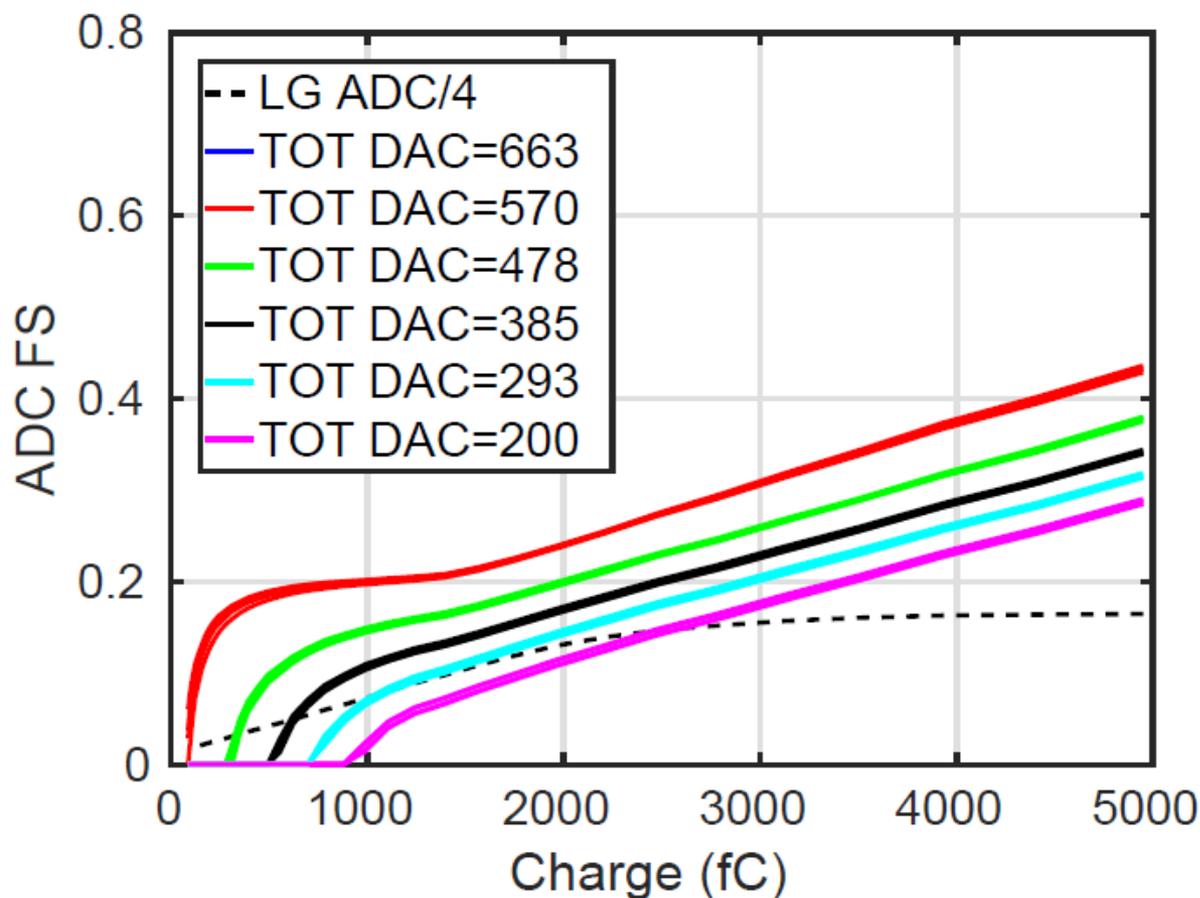


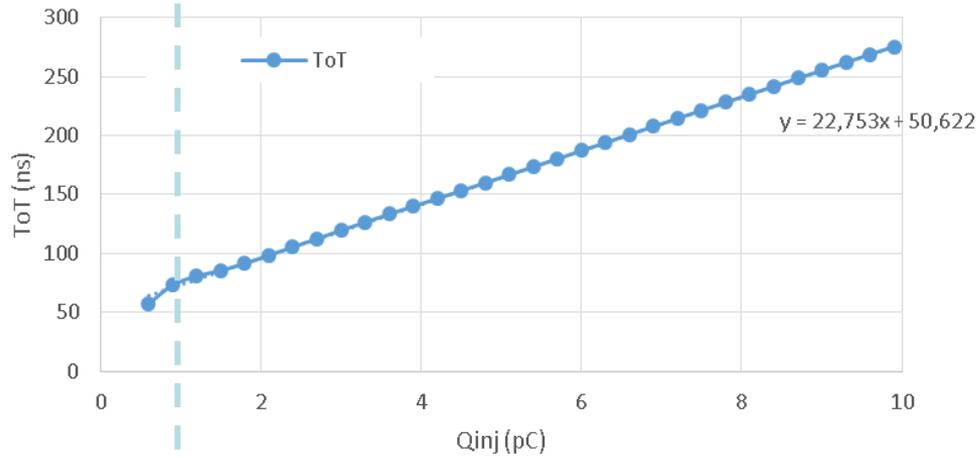
Figure 16: TOT S-curves at 100 fC

- TOT measurements starting...

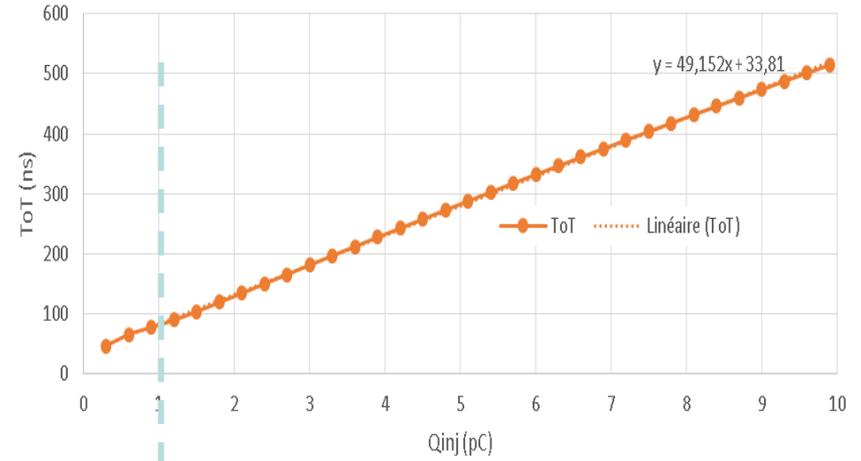
TOT VS HG/LG, -30C



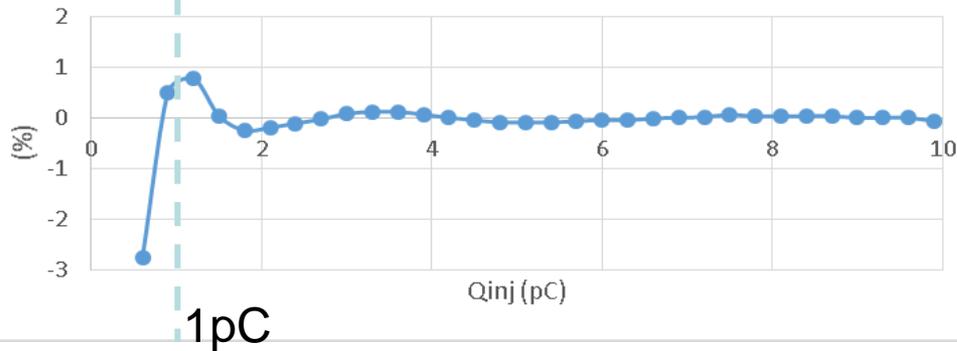
Time over Threshold
positive input



Time over Threshold
negative input

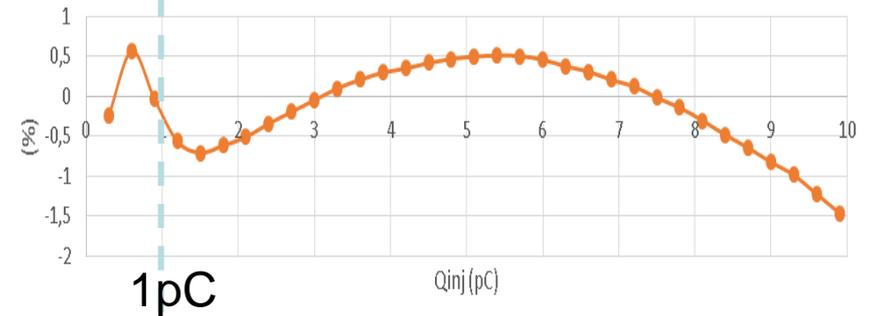


residuals



Low gain Saturation

residuals



Low gain Saturation

- High speed discriminator after fast shaper (4 ns)
- Threshold at 10 fC and 30 fC
- Preliminary timing performance : 270 ps at 30 fC and 57 ps at 300 fC
- Will allow system level studies....

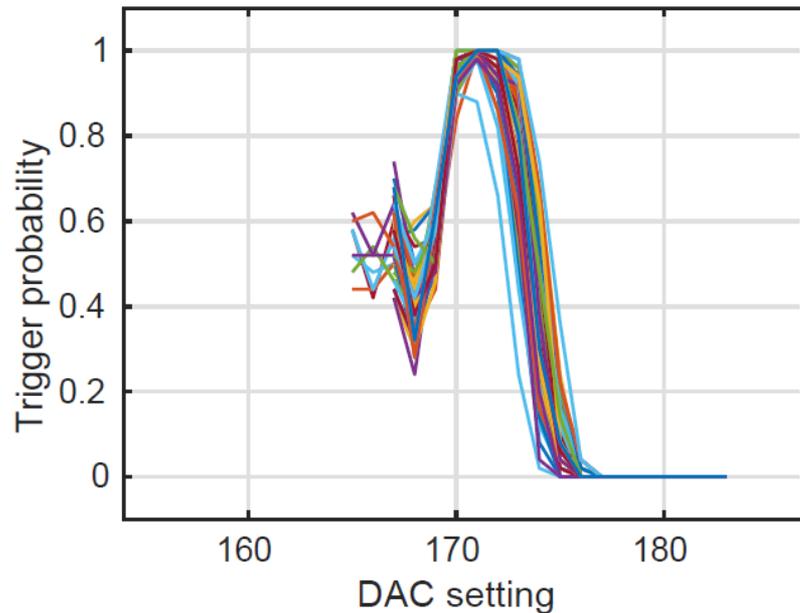


Figure 1: TOA S-curves at 10 fC

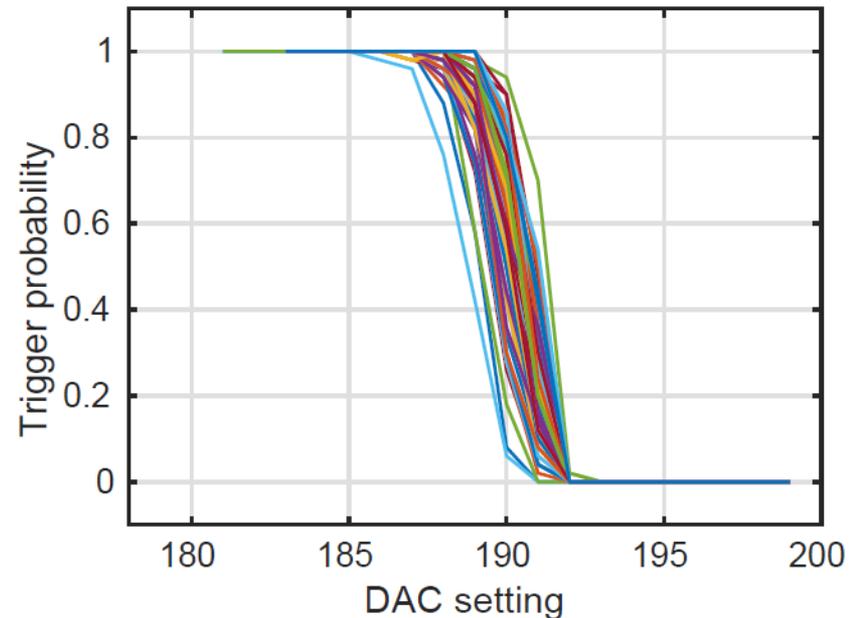
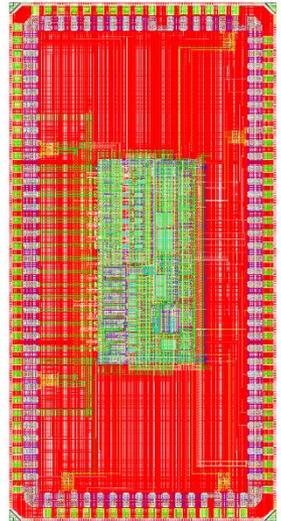
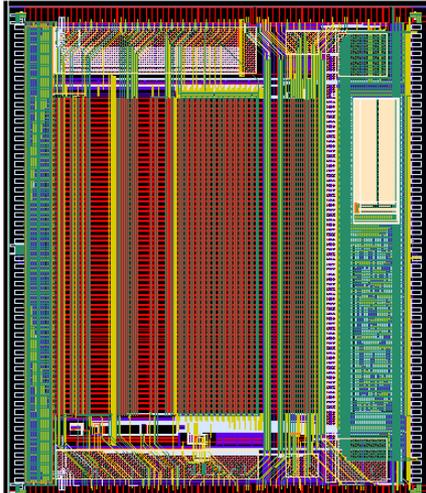


Figure 4: TOA S-curves at 32 fC

- SKIROC2_CMS is a versatile chip for Si pads
 - 64 ch dual polarity charge/current preamplifier
 - HG/LG variable shaper 10-75 ns
 - 13 deep 40 MHz analog memory for event buffering
 - Fast branch (5 ns) for timing TOA and TOT
 - Internal 12 bit ADC/TDC
- SKIROC2_CMS for HGCal testbeam operation
 - Will be used to validate HGCal readout architecture
 - Front-end boards studies and system tests

- SKIROC2_CMS received beg june
 - Preliminary tests shown here
- Test vehicle 1 submitted in may
 - Various preamp flavours, shapers, discriminators
 - TSMC130nm, received last week
- Test vehicle 2 foreseen in the fall
 - Different variants of a full one channel
- 64ch chip HGROC V1 foreseen june 2017
 - Collaboration AGH, CERN, Imperial, CEA/IRFU



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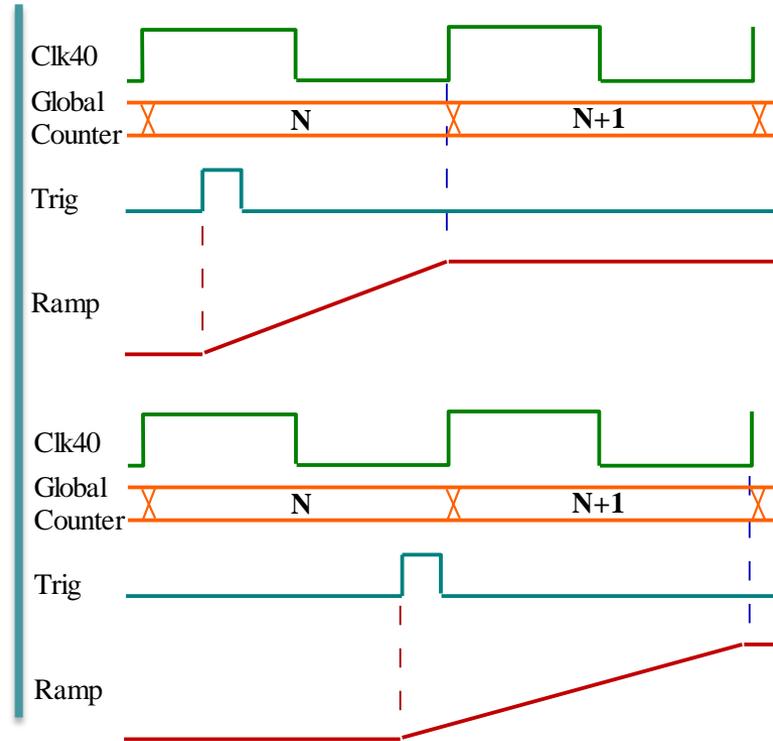
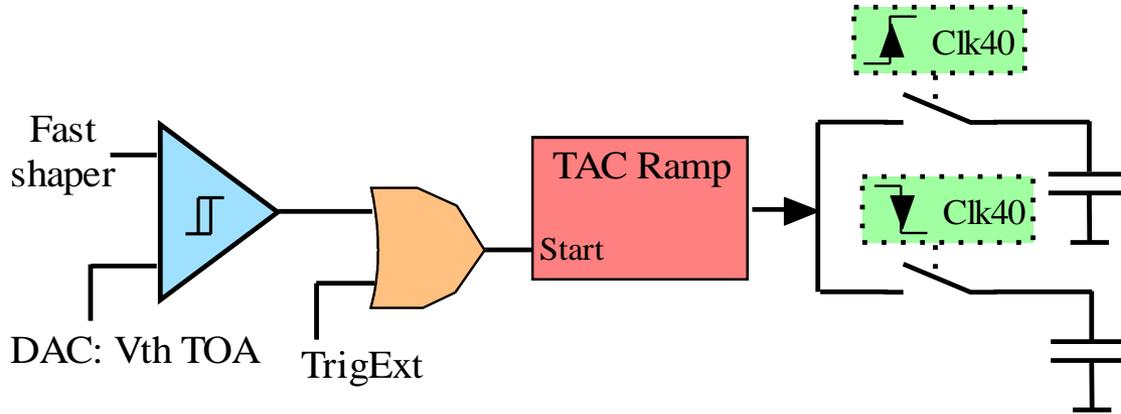
irfu
cea
sacalay

OMEGA
Microelectronics

Time of Arrival principle (TOA)

TOA based on a Time to Amplitude Converter (TAC):

- ❑ 1 analog ramp / channel sampled on clock edges (both)
- ❑ 1 global counter @ 40 MHz sampled with OR64_TOA
- ❑ 1 global TrigExt available to calibrate ramps

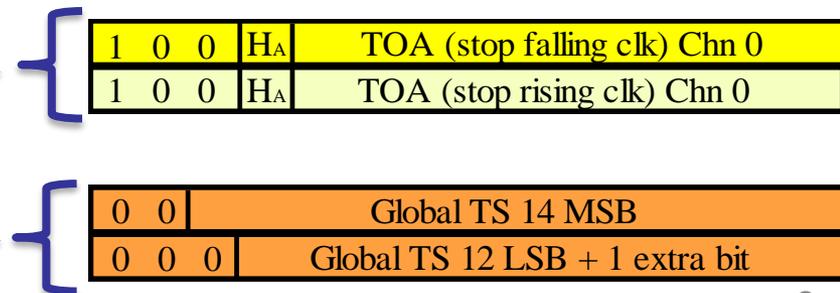


❑ If needed, pulse shape in “rolling” SCA used to mitigate counter value (multi-hits)

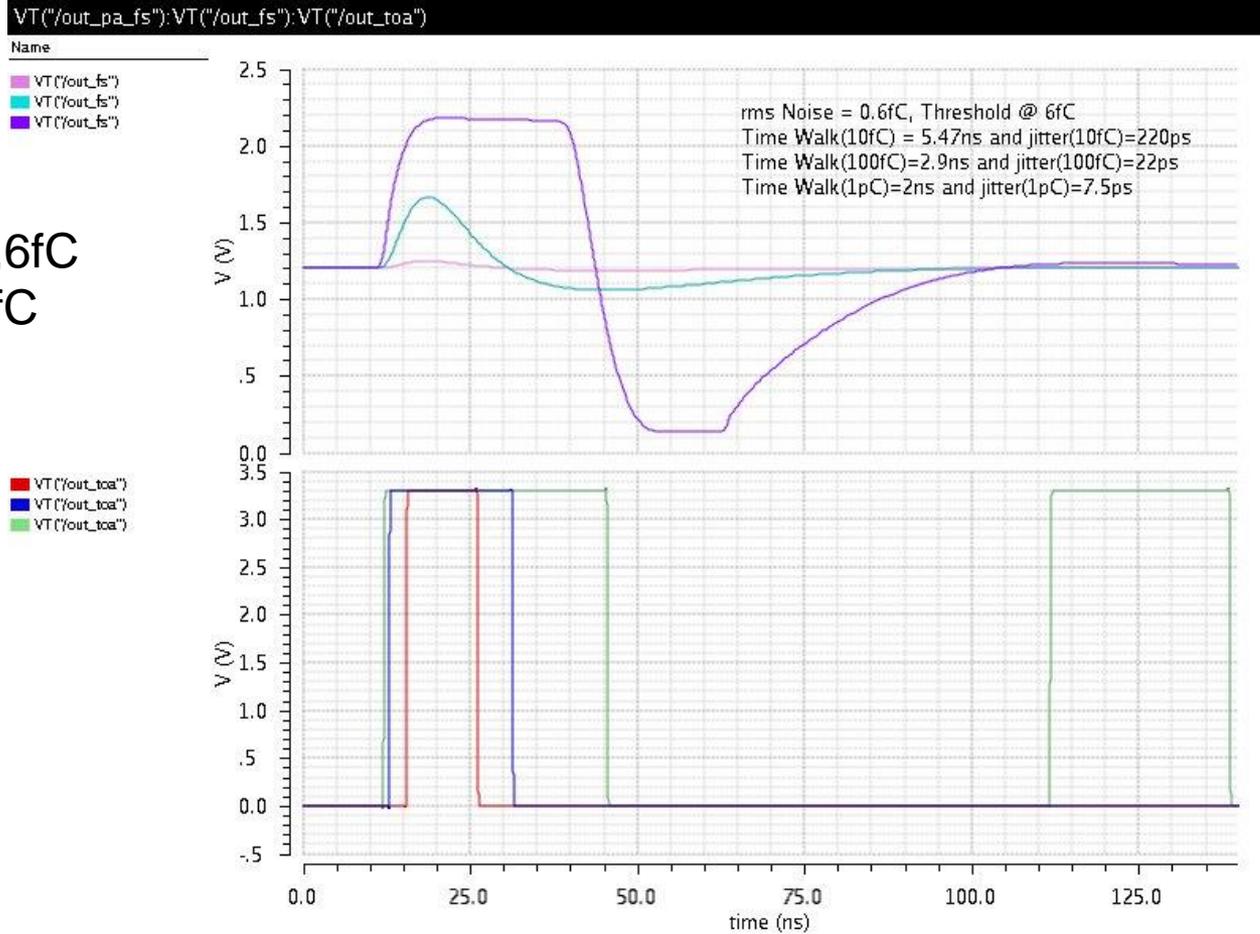
❑ Channel with TOA data are marked with Hit bit

❑ Relevant data in memory mapping:

- ❑ Digitized TAC ramp (both edged)
- ❑ Hit bit (H_A)
- ❑ Global counter value @ 40 MHz



Rms Noise = 0,6fC
Threshold @ 6fC



Qinj(fC)	Time walk (ns)	Jitter (ps)
10	5,47	220
100	2,9	22
1000	2	7,5

- Using direct and alternate sums (DS and AS) on n channels (n=64)
- Incoherent noise $IN=AS/\sqrt{n}$
- Coherent noise : $CN = \sqrt{DS^2 - AS^2} /n$
- Coherent noise fraction : $CF = CN/IN$

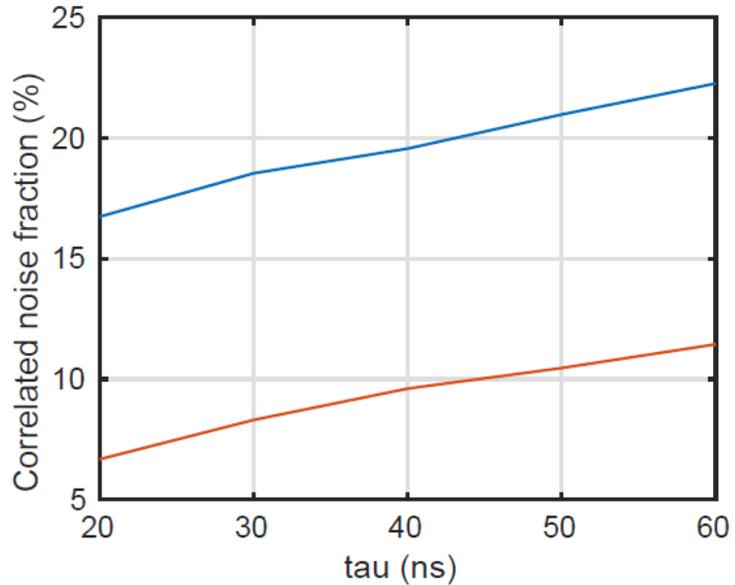
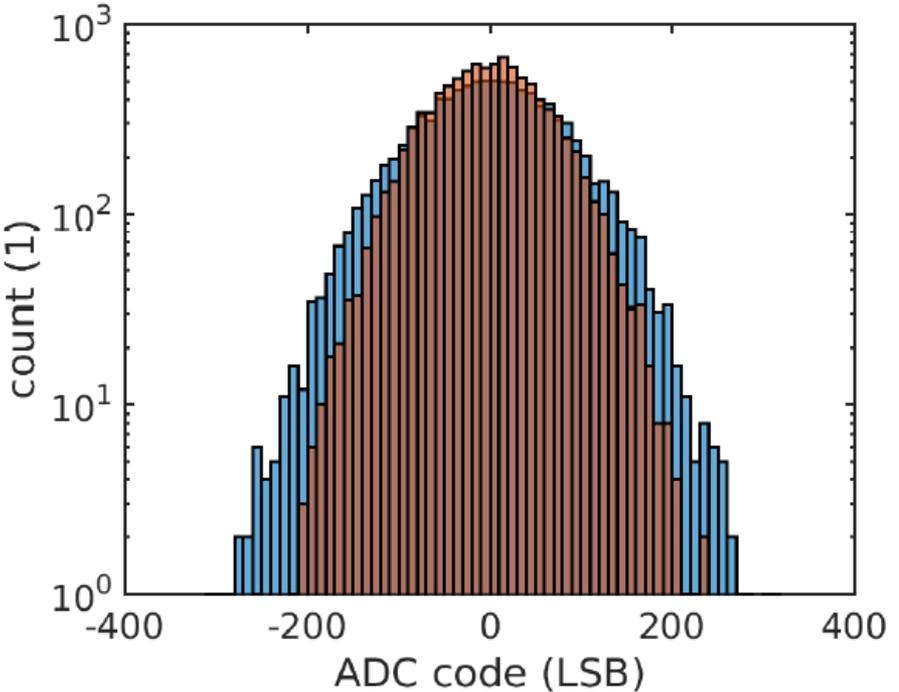
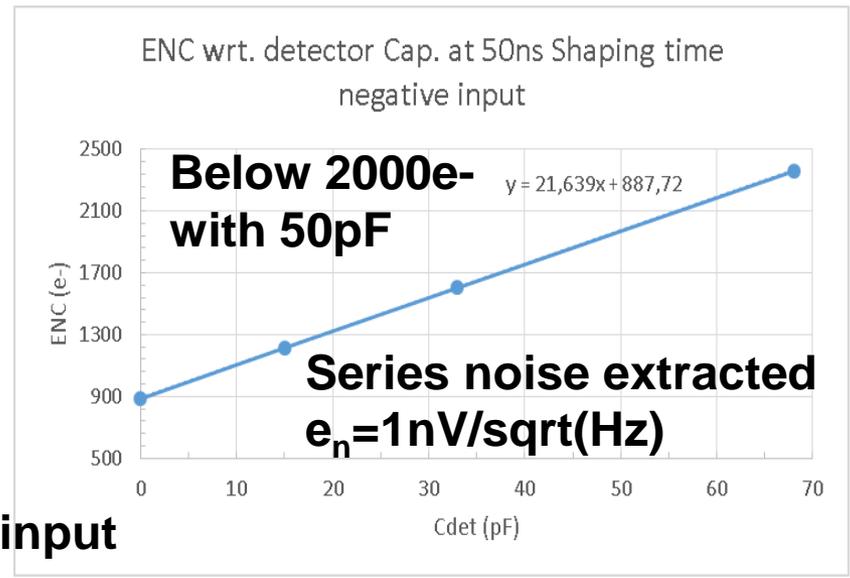
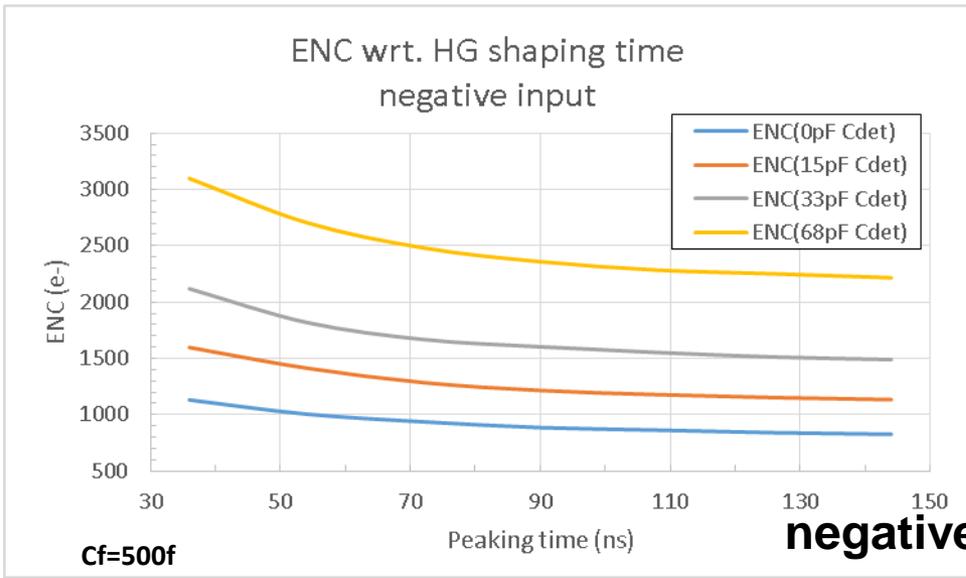
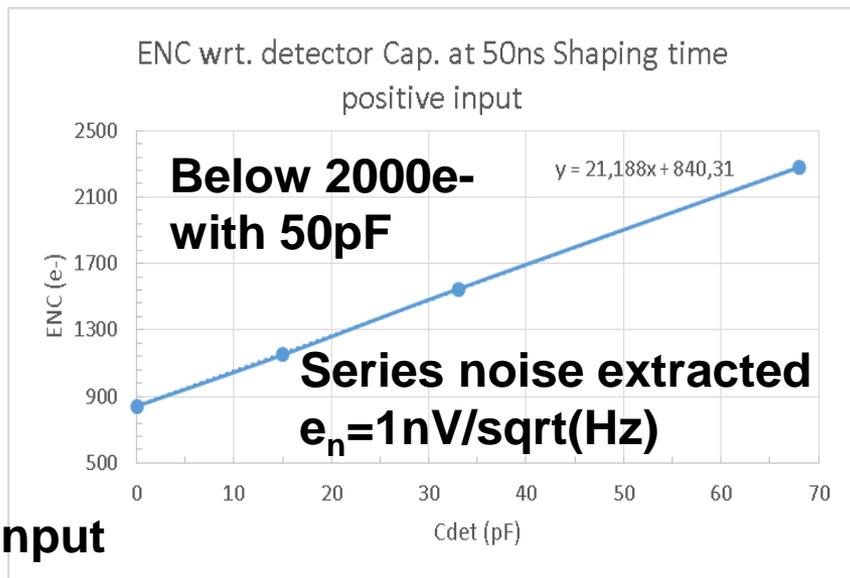
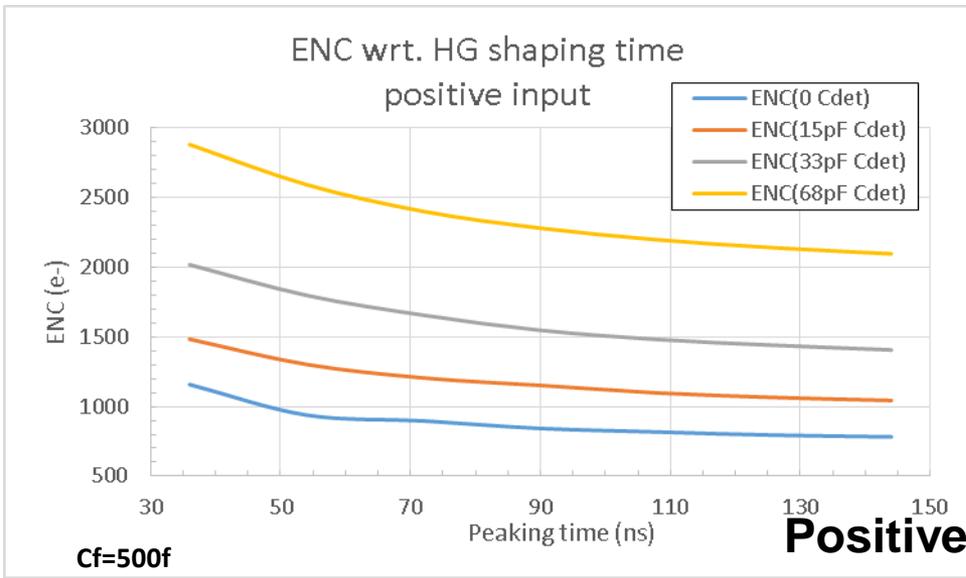
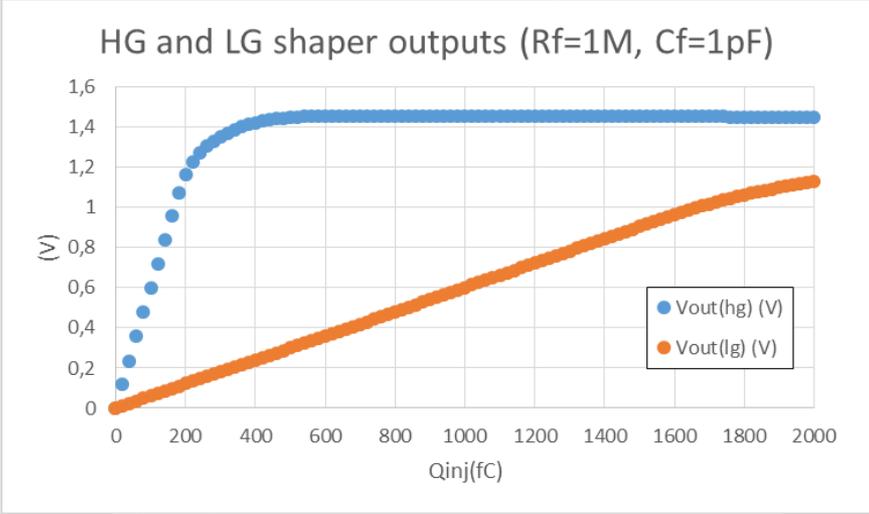


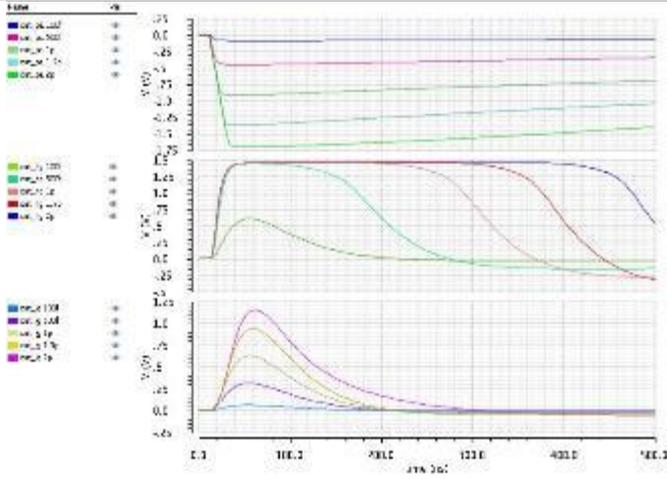
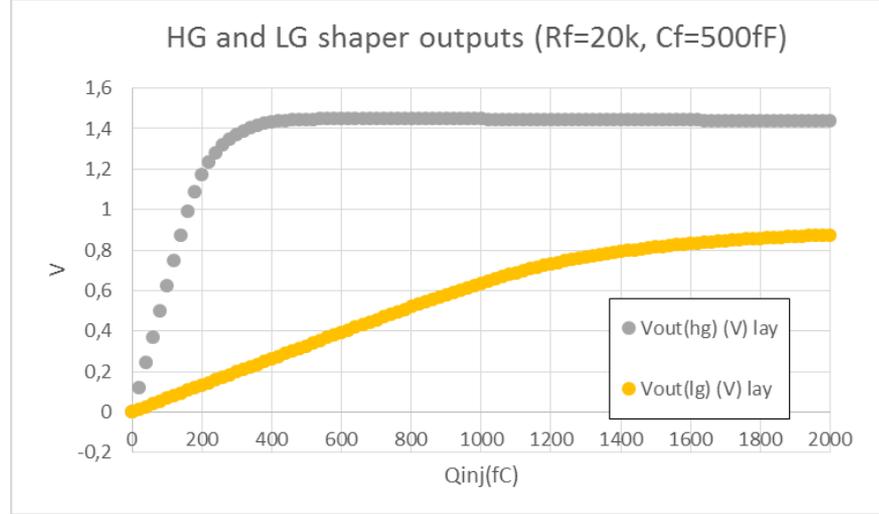
Figure 22: Correlated noise fraction (correlated/white)



Charge PA
Rf=1M, Cf=1pF



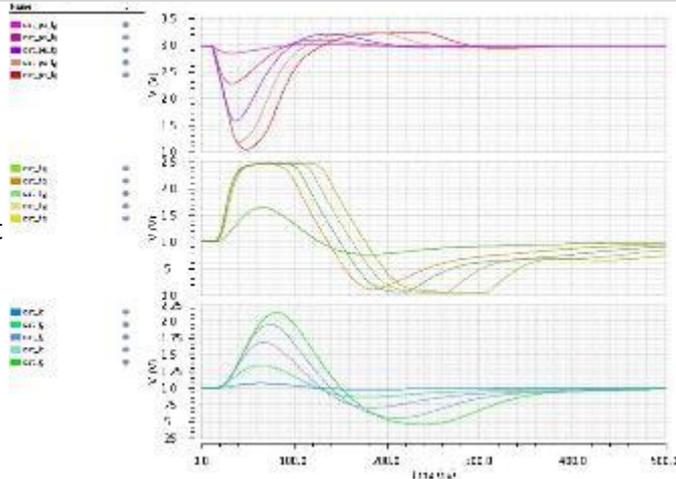
Current PA
Rf=20k, Cf=500fF



Preamp output

HG shaper output

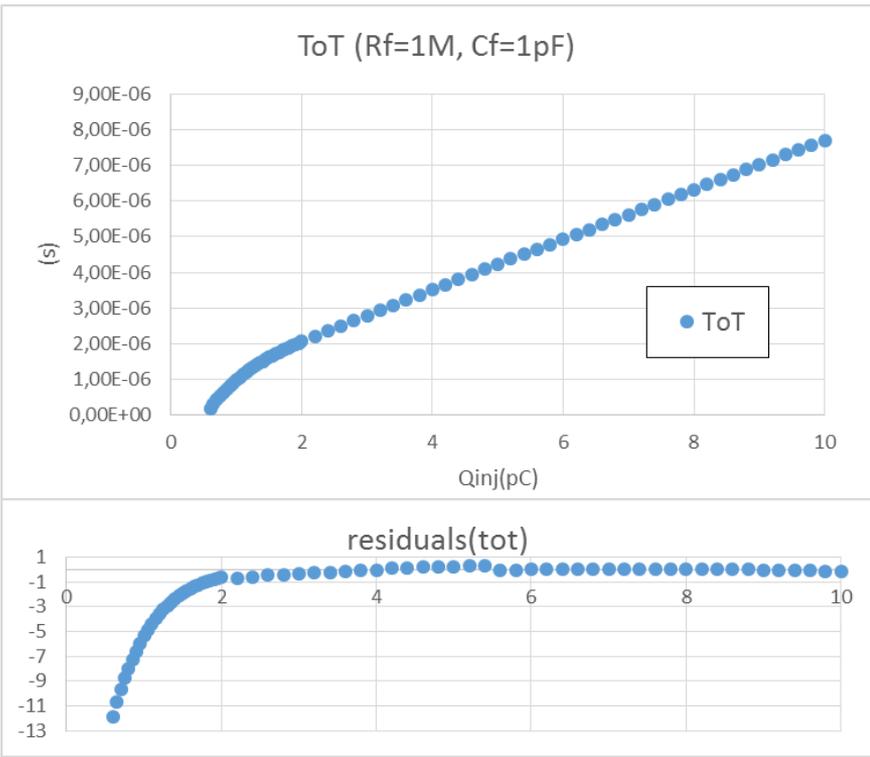
LG shaper output



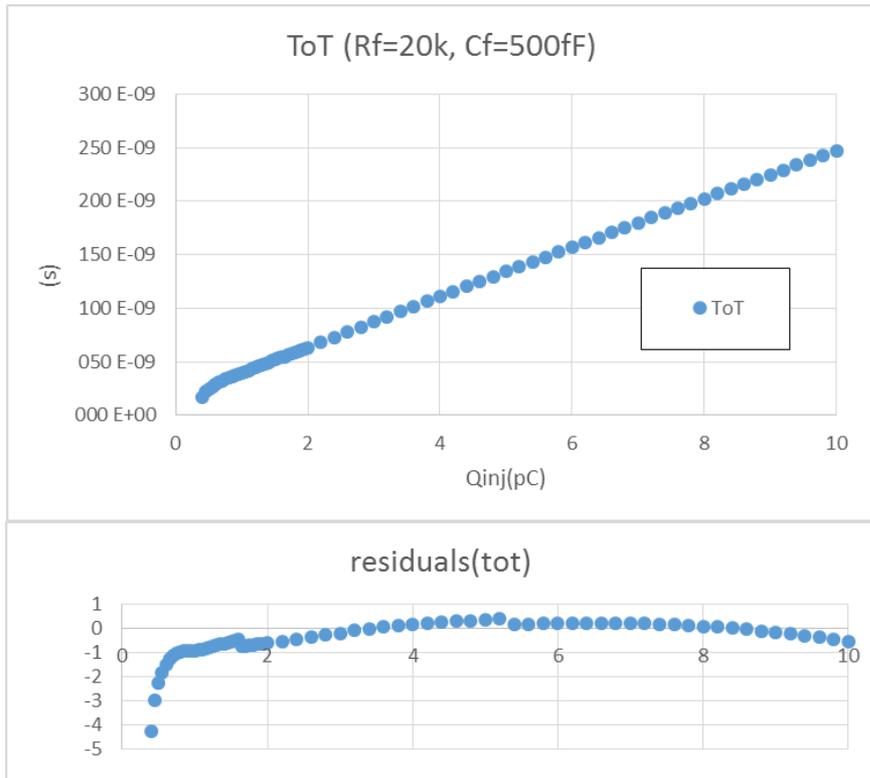
- HG linearity: from 0 to 180 fC
- LG linearity: from 0 to 1700 fC

- HG linearity: from 0 to 160 fC
- LG linearity: from 0 to 950 fC

Charge PA
Rf=1M, Cf=1pF



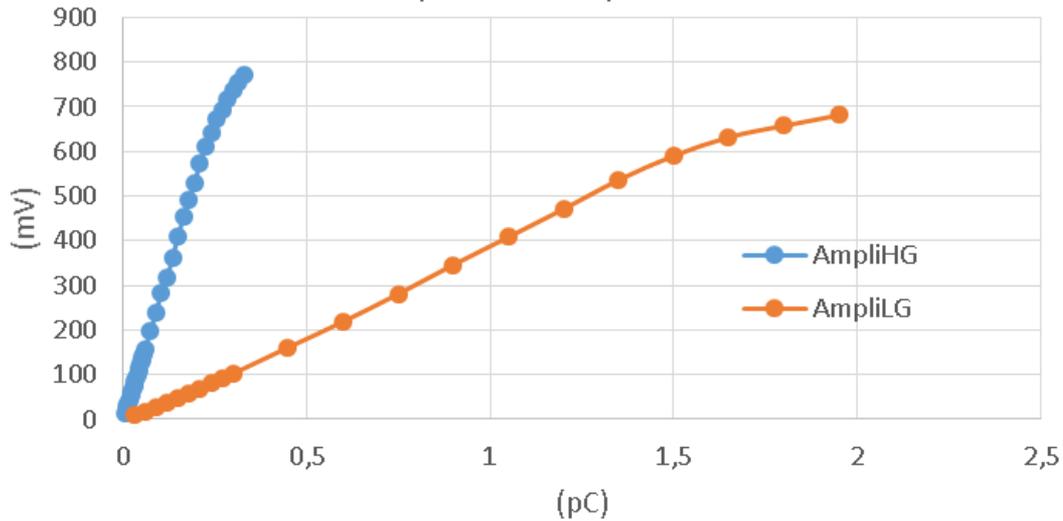
Current PA
Rf=20k, Cf=500fF



- Threshold @ 700 fC
- ToT linearity: from 800 fC to 10 pC

- Threshold @ 450 fC
- ToT linearity: from 1,7 pC to 10 pC

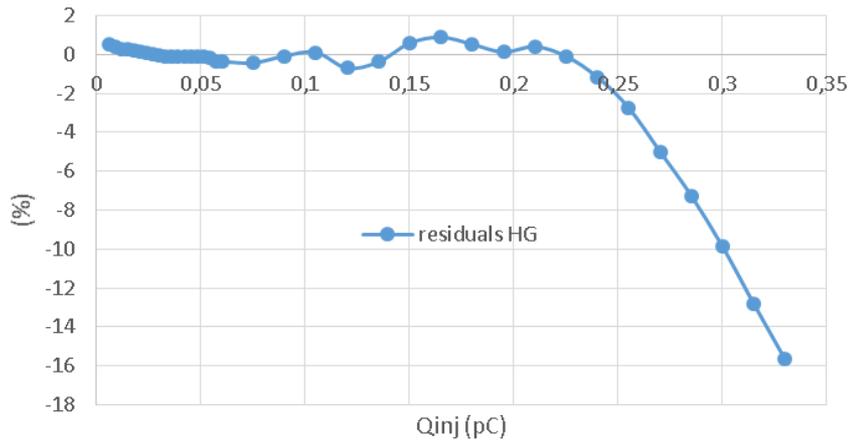
HG & LG linearities
positive input



Setup:
Cf=500fF,
Rf=30k,
Cd=68pF
Tau = 40ns

linearity better than
1% up to 250fC for HG
and 1pC for LG

residuals HG



residuals LG

